

LH28F800BG-L/BGH-L (FOR TSOP, CSP)

8 M-bit (512 kB x 16) SmartVoltage Flash Memories

DESCRIPTION

The LH28F800BG-L/BGH-L flash memories with SmartVoltage technology are high-density, low-cost, nonvolatile, read/write storage solution for a wide range of applications. The LH28F800BG-L/BGH-L can operate at $V_{CC} = 2.7\text{ V}$ and $V_{PP} = 2.7\text{ V}$. Their low voltage operation capability realizes longer battery life and suits for cellular phone application. Their boot, parameter and main-blocked architecture, flexible voltage and enhanced cycling capability provide for highly flexible component suitable for portable terminals and personal computers. Their enhanced suspend capabilities provide for an ideal solution for code + data storage applications. For secure code storage applications, such as networking, where code is either directly executed out of flash or downloaded to DRAM, the LH28F800BG-L/BGH-L offer two levels of protection : absolute protection with V_{PP} at GND, selective hardware boot block locking. These alternatives give designers ultimate control of their code security needs.

FEATURES

- SmartVoltage technology
 - 2.7 V, 3.3 V or 5 V V_{CC}
 - 2.7 V, 3.3 V, 5 V or 12 V V_{PP}
- High performance read access time
 - LH28F800BG-L85/BGH-L85
 - 85 ns (5.0±0.25 V)/90 ns (5.0±0.5 V)/
 - 100 ns (3.3±0.3 V)/120 ns (2.7 to 3.6 V)
 - LH28F800BG-L12/BGH-L12
 - 120 ns (5.0±0.5 V)/130 ns (3.3±0.3 V)/
 - 150 ns (2.7 to 3.6 V)
- Enhanced automated suspend options
 - Word write suspend to read
 - Block erase suspend to word write
 - Block erase suspend to read
- Enhanced data protection features
 - Absolute protection with $V_{PP} = \text{GND}$
 - Block erase/word write lockout during power transitions
 - Boot blocks protection with $WP\# = V_{IL}$
- SRAM-compatible write interface
- Optimized array blocking architecture
 - Two 4 k-word boot blocks
 - Six 4 k-word parameter blocks
 - Fifteen 32 k-word main blocks
 - Top or bottom boot location
- Enhanced cycling capability
 - 100 000 block erase cycles
- Low power management
 - Deep power-down mode
 - Automatic power saving mode decreases I_{CC} in static mode
- Automated word write and block erase
 - Command user interface
 - Status register
- ETOX™* V nonvolatile flash technology
- Packages
 - 48-pin TSOP Type I (TSOP048-P-1220)
Normal bend/Reverse bend
 - 48-ball CSP (FBGA048-P-0808)

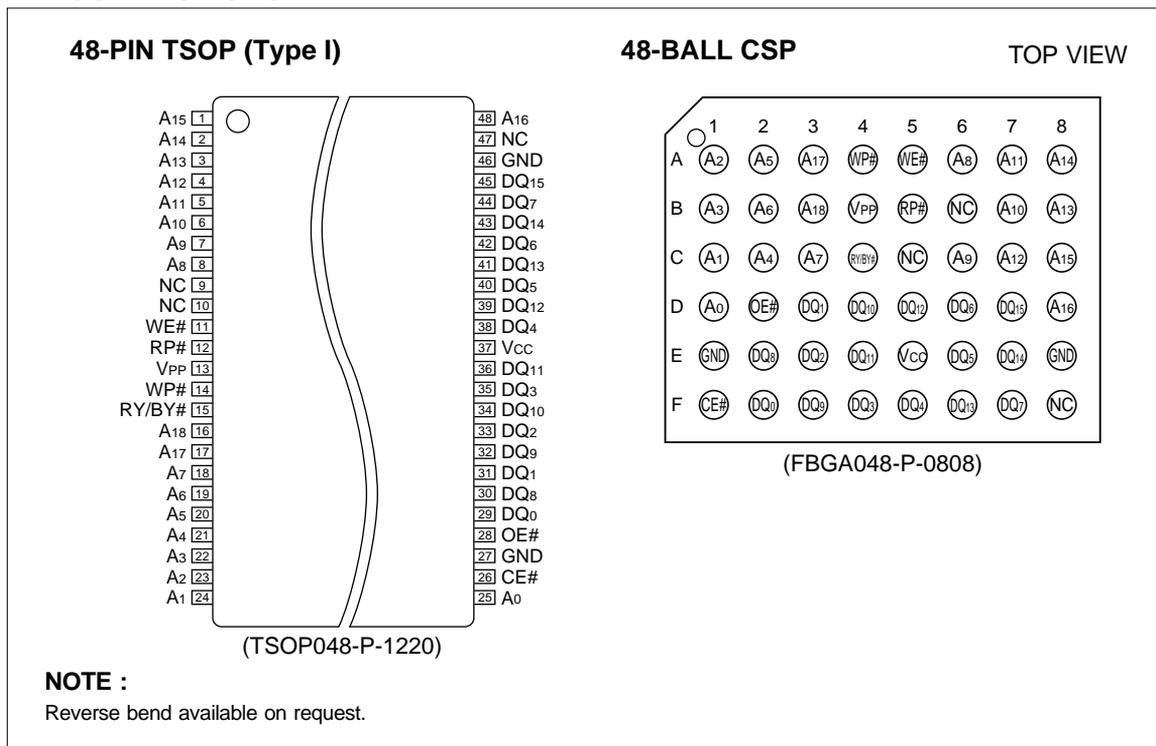
* ETOX is a trademark of Intel Corporation.

COMPARISON TABLE

VERSIONS	OPERATING TEMPERATURE	PACKAGE	DC CHARACTERISTICS Vcc deep power-down current (MAX.)	WRITE PROTECT FUNCTION FOR BOOT BLOCKS
LH28F800BG-L (FOR TSOP, CSP)	0 to +70°C	48-pin TSOP (I) 48-ball CSP	10 µA	Controlled by WP# and RP# pins
LH28F800BGH-L (FOR TSOP, CSP)	-40 to +85°C	48-pin TSOP (I) 48-ball CSP	20 µA	Controlled by WP# and RP# pins
LH28F800BG-L*1 (FOR SOP)	0 to +70°C	44-pin SOP	10 µA	Controlled by RP# pin

*1 Refer to the datasheet of LH28F800BG-L (FOR SOP).

PIN CONNECTIONS



BLOCK ORGANIZATION

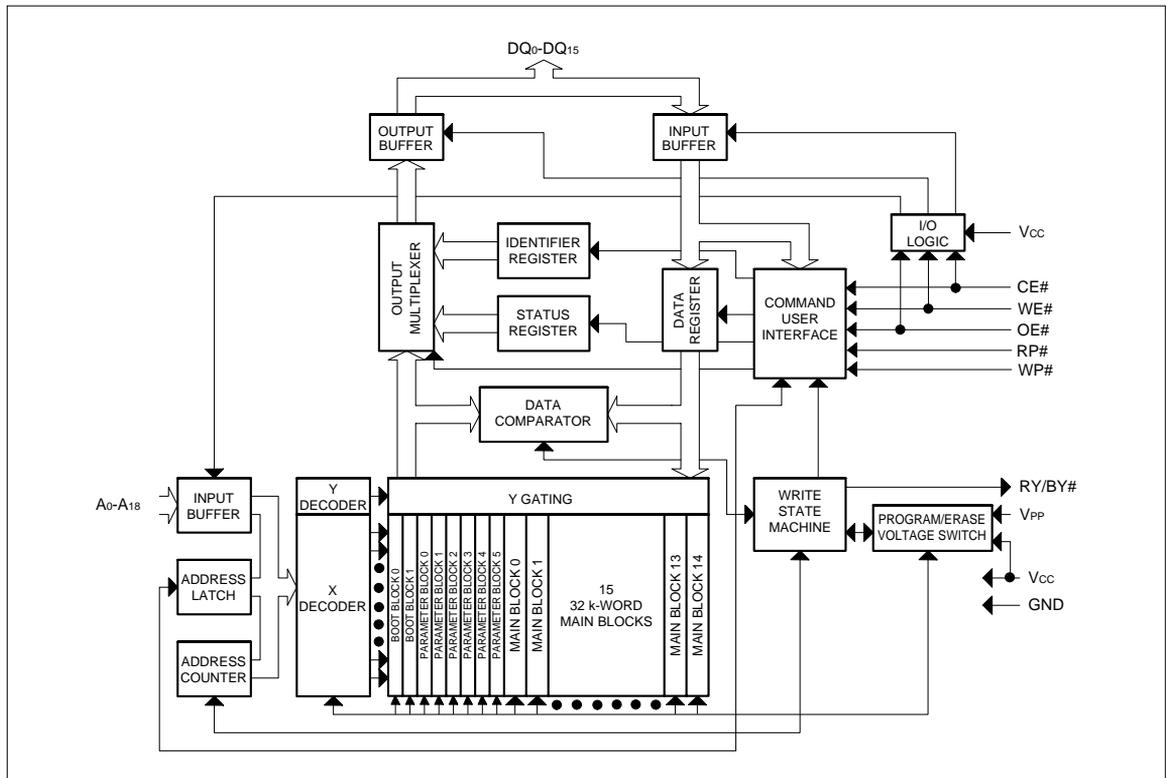
This product features an asymmetrically-blocked architecture providing system memory integration. Each erase block can be erased independently of the others up to 100 000 times. For the address locations of the blocks, see the memory map in **Fig. 1**.

Boot Blocks : The two boot blocks are intended to replace a dedicated boot PROM in a micro-processor or microcontroller-based system. The boot blocks of 4 k words (4 096 words) feature hardware controllable write-protection to protect the crucial microprocessor boot code from accidental modification. The protection of the boot blocks is controlled using a combination of the V_{PP}, RP# and WP# pins.

Parameter Blocks : The boot block architecture includes parameter blocks to facilitate storage of frequently update small parameters that would normally require an EEPROM. By using software techniques, the byte-rewrite functionality of EEPROMs can be emulated. Each boot block component contains six parameter blocks of 4 k words (4 096 words) each. The parameter blocks are not write-protectable.

Main Blocks : The remainder is divided into main blocks for data or code storage. Each 8 M-bit device contains fifteen 32 k words (32 768 words) blocks.

BLOCK DIAGRAM



PIN DESCRIPTION

SYMBOL	TYPE	NAME AND FUNCTION
A ₀ -A ₁₈	INPUT	ADDRESS INPUTS : Inputs for addresses during read and write operations. Addresses are internally latched during a write cycle.
DQ ₀ -DQ ₁₅	INPUT/ OUTPUT	DATA INPUT/OUTPUTS : Inputs data and commands during CUI write cycles; outputs data during memory array, status register and identifier code read cycles. Data pins float to high-impedance when the chip is deselected or outputs are disabled. Data is internally latched during a write cycle.
CE#	INPUT	CHIP ENABLE : Activates the device's control logic, input buffers, decoders and sense amplifiers. CE#-high deselects the device and reduces power consumption to standby levels.
RP#	INPUT/	RESET/DEEP POWER-DOWN : Puts the device in deep power-down mode and resets internal automation. RP#-high enables normal operation. When driven low, RP# inhibits write operations which provide data protection during power transitions. Exit from deep power-down sets the device to read array mode. With RP# = V _{HH} , block erase or word write can operate to all blocks without WP# state. Block erase or word write with V _{IH} < RP# < V _{HH} produce spurious results and should not be attempted.
OE#	INPUT	OUTPUT ENABLE : Gates the device's outputs during a read cycle.
WE#	INPUT	WRITE ENABLE : Controls writes to the CUI and array blocks. Addresses and data are latched on the rising edge of the WE# pulse.
WP#	INPUT	WRITE PROTECT : Master control for boot blocks locking. When V _{IL} , locked boot blocks cannot be erased and programmed.
RY/BY#	OUTPUT	READY/BUSY : Indicates the status of the internal WSM. When low, the WSM is performing an internal operation (block erase or word write). RY/BY#-high indicates that the WSM is ready for new commands, block erase is suspended, and word write is inactive, word write is suspended, or the device is in deep power-down mode. RY/BY# is always active and does not float when the chip is deselected or data outputs are disabled.
V _{PP}	SUPPLY	BLOCK ERASE AND WORD WRITE POWER SUPPLY : For erasing array blocks or writing words. With V _{PP} ≤ V _{PPLK} , memory contents cannot be altered. Block erase and word write with an invalid V _{PP} (see Section 6.2.3 "DC CHARACTERISTICS") produce spurious results and should not be attempted.
V _{CC}	SUPPLY	DEVICE POWER SUPPLY : Internal detection configures the device for 2.7 V, 3.3 V or 5 V operation. To switch from one voltage to another, ramp V _{CC} down to GND and then ramp V _{CC} to the new voltage. Do not float any power pins. With V _{CC} ≤ V _{LKO} , all write attempts to the flash memory are inhibited. Device operations at invalid V _{CC} voltage (see Section 6.2.3 "DC CHARACTERISTICS") produce spurious results and should not be attempted.
GND	SUPPLY	GROUND : Do not float any ground pins.
NC		NO CONNECT : Lead is not internal connected; recommend to be floated.

1 INTRODUCTION

This datasheet contains LH28F800BG-L/BGH-L specifications. Section 1 provides a flash memory overview. Sections 2, 3, 4 and 5 describe the memory organization and functionality. Section 6 covers electrical specifications. LH28F800BG-L/BGH-L flash memories documentation also includes ordering information which is referenced in Section 7.

1.1 New Features

Key enhancements of LH28F800BG-L/BGH-L SmartVoltage flash memories are :

- SmartVoltage Technology
- Enhanced Suspend Capabilities
- Boot Block Architecture

Note following important differences :

- VPP_{PLK} has been lowered to 1.5 V to support 2.7 V, 3.3 V and 5 V block erase and word write operations. Designs that switch VPP off during read operations should make sure that the VPP voltage transitions to GND.
- To take advantage of SmartVoltage technology, allow VPP connection to 2.7 V, 3.3 V or 5 V.

1.2 Product Overview

The LH28F800BG-L/BGH-L are high-performance 8 M-bit SmartVoltage flash memories organized as 512 k-word of 16 bits. The 512 k-word of data is arranged in two 4 k-word boot blocks, six 4 k-word parameter blocks and fifteen 32 k-word main blocks which are individually erasable in-system. The memory map is shown in **Fig. 1**.

SmartVoltage technology provides a choice of V_{CC} and V_{PP} combinations, as shown in **Table 1**, to meet system performance and power expectations. 2.7 V V_{CC} consumes approximately one-fifth the power of 5 V V_{CC} and 3.3 V V_{CC} consumes approximately one-fourth the power of 5 V V_{CC}.

But, 5 V V_{CC} provides the highest read performance. V_{PP} at 2.7 V, 3.3 V and 5 V eliminates the need for a separate 12 V converter, while V_{PP} = 12 V maximizes block erase and word write performance. In addition to flexible erase and program voltages, the dedicated V_{PP} pin gives complete data protection when $V_{PP} \leq V_{PPLK}$.

Table 1 V_{CC} and V_{PP} Voltage Combinations Offered by SmartVoltage Technology

V _{CC} VOLTAGE	V _{PP} VOLTAGE
2.7 V	2.7 V, 3.3 V, 5 V, 12 V
3.3 V	3.3 V, 5 V, 12 V
5 V	5 V, 12 V

Internal V_{CC} and V_{PP} detection circuitry automatically configures the device for optimized read and write operations.

A Command User Interface (CUI) serves as the interface between the system processor and internal operation of the device. A valid command sequence written to the CUI initiates device automation. An internal Write State Machine (WSM) automatically executes the algorithms and timings necessary for block erase and word write operations.

A block erase operation erases one of the device's 32 k-word blocks typically within 0.39 second (5 V V_{CC}, 12 V V_{PP}), 4 k-word blocks typically within 0.25 second (5 V V_{CC}, 12 V V_{PP}) independent of other blocks. Each block can be independently erased 100 000 times. Block erase suspend mode allows system software to suspend block erase to read data from, or write data to any other block.

Writing memory data is performed in word increments of the device's 32 k-word blocks typically within 8.4 μs (5 V V_{CC}, 12 V V_{PP}), 4 k-word blocks typically within 17 μs (5 V V_{CC}, 12 V V_{PP}). Word write suspend mode enables the

system to read data from, or write to any other flash memory array location.

The boot block is located at either the top or the bottom of the address map in order to accommodate different micro-processor protect for boot code location. The hardware-lockable boot block provides complete code security for the kernel code required for system initialization. Locking and unlocking of the boot block is controlled by WP# and/or RP# (see **Section 4.9** for details). Block erase or word write for boot block must not be carried out by WP# to low and RP# to VIH.

The status register indicates when the WSM's block erase or word write operation is finished.

The RY/BY# output gives an additional indicator of WSM activity by providing both a hardware signal of status (versus software polling) and status masking (interrupt masking for background block erase, for example). Status polling using RY/BY# minimizes both CPU overhead and system power consumption. When low, RY/BY# indicates that the WSM is performing a block erase or word write. RY/BY#-high indicates that the WSM is ready for a new command, block erase is suspended (and word write is inactive), word write is suspended, or the device is in deep power-down mode.

The access time is 85 ns (t_{AVQV}) at the Vcc supply voltage range of 4.75 to 5.25 V over the temperature range, 0 to +70°C (LH28F800BG-L)/ -40 to +85°C (LH28F800BGH-L). At 4.5 to 5.5 V Vcc, the access time is 90 ns or 120 ns. At lower Vcc voltage, the access time is 100 ns or 130 ns (3.0 to 3.6 V) and 120 ns or 150 ns (2.7 to 3.6 V).

The Automatic Power Saving (APS) feature substantially reduces active current when the device is in static mode (addresses not switching). In APS mode, the typical ICCR current is 1 mA at 5 V Vcc and 3 mA at 2.7 V and 3.3 V Vcc.

When CE# and RP# pins are at Vcc, the Icc CMOS standby mode is enabled. When the RP# pin is at GND, deep power-down mode is enabled which minimizes power consumption and provides write protection during reset. A reset time (t_{PHQV}) is required from RP# switching high until outputs are valid. Likewise, the device has a wake time (t_{PHEL}) from RP#-high until writes to the CUI are recognized. With RP# at GND, the WSM is reset and the status register is cleared.

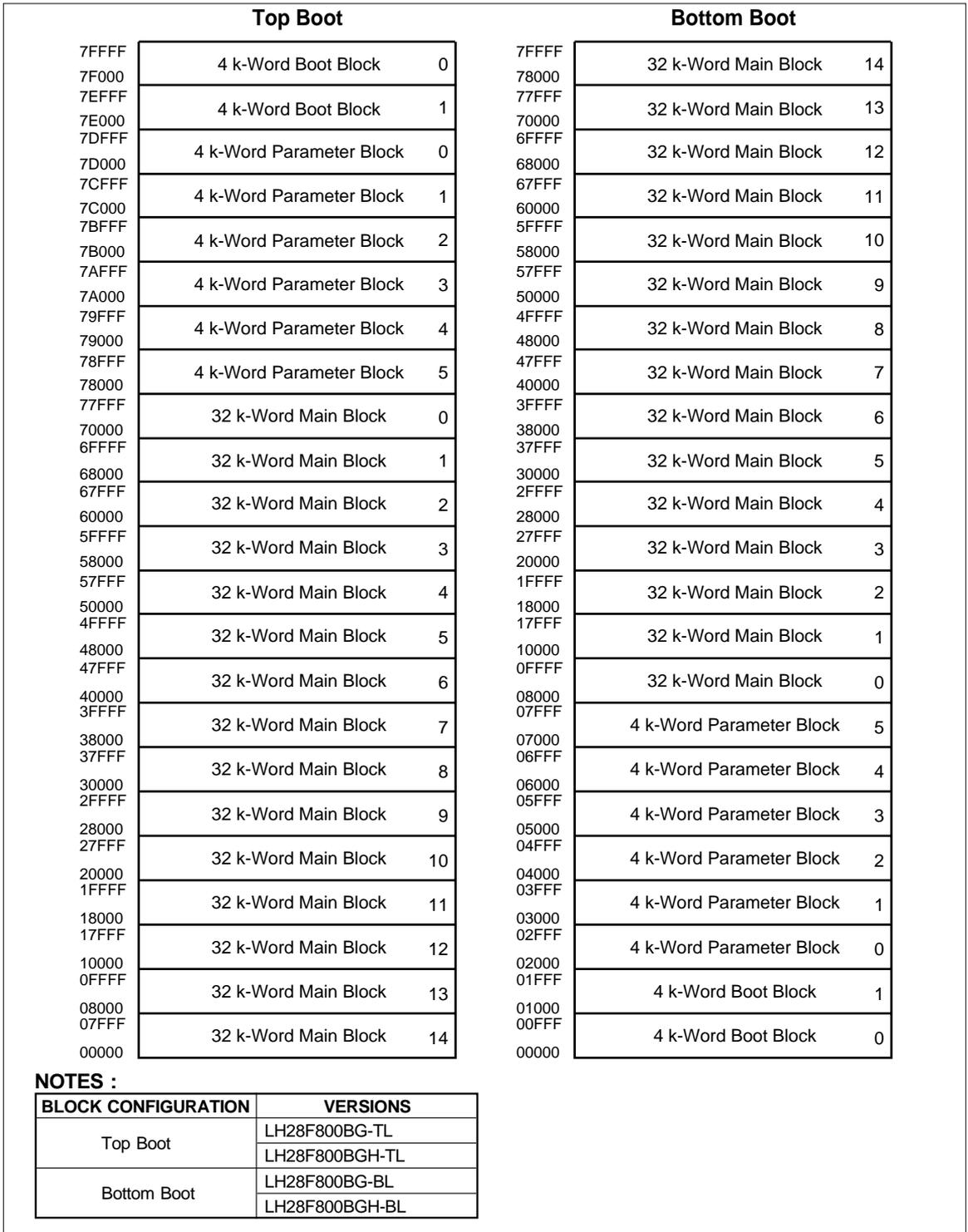


Fig. 1 Memory Map

2 PRINCIPLES OF OPERATION

The LH28F800BG-L/BGH-L SmartVoltage flash memories include an on-chip WSM to manage block erase and word write functions. It allows for : 100% TTL-level control inputs, fixed power supplies during block erasure and word write, and minimal processor overhead with RAM-like interface timings.

After initial device power-up or return from deep power-down mode (see **Table 2 "Bus Operations"**), the device defaults to read array mode. Manipulation of external memory control pins allow array read, standby and output disable operations.

Status register and identifier codes can be accessed through the CUI independent of the VPP voltage. High voltage on VPP enables successful block erasure and word writing. All functions associated with altering memory contents—block erase, word write, status and identifier codes—are accessed via the CUI and verified through the status register.

Commands are written using standard micro-processor write timings. The CUI contents serve as input to the WSM, which controls the block erase and word write. The internal algorithms are regulated by the WSM, including pulse repetition, internal verification and margining of data. Addresses and data are internally latched during write cycles. Writing the appropriate command outputs array data, accesses the identifier codes or outputs status register data.

Interface software that initiates and polls progress of block erase and word write can be stored in any block. This code is copied to and executed from system RAM during flash memory updates. After successful completion, reads are again possible via the Read Array command. Block erase suspend allows system software to suspend a block erase to read/write data from/to blocks other than that which is suspended. Word write suspend allows system

software to suspend a word write to read data from any other flash memory array location.

2.1 Data Protection

Depending on the application, the system designer may choose to make the VPP power supply switchable (available only when memory block erases or word writes are required) or hardwired to VPPH1/2/3. The device accommodates either design practice and encourages optimization of the processor-memory interface.

When $V_{PP} \leq V_{PPLK}$, memory contents cannot be altered. The CUI, with two-step block erase or word write command sequences, provides protection from unwanted operations even when high voltage is applied to VPP. All write functions are disabled when VCC is below the write lockout voltage VLKO or when RP# is at VIL. The device's boot blocks locking capability for WP# provides additional protection from inadvertent code or data alteration by block erase and word write operations.

3 BUS OPERATION

The local CPU reads and writes flash memory in-system. All bus cycles to or from the flash memory conform to standard microprocessor bus cycles.

3.1 Read

Information can be read from any block, identifier codes or status register independent of the VPP voltage. RP# can be at either VIH or VHH.

The first task is to write the appropriate read mode command (Read Array, Read Identifier Codes or Read Status Register) to the CUI. Upon initial device power-up or after exit from deep power-down mode, the device automatically resets to read array mode. Five control pins dictate the data flow in and out of the component : CE#, OE#, WE#, RP# and WP#. CE# and OE# must be driven active to obtain data at the outputs. CE# is the

device selection control, and when active enables the selected memory device. OE# is the data output (DQ0-DQ15) control and when active drives the selected memory data onto the I/O bus. WE# must be at V_{IH} and RP# must be at V_{IH} or V_{HH}. Fig. 11 illustrates read cycle.

3.2 Output Disable

With OE# at a logic-high level (V_{IH}), the device outputs are disabled. Output pins (DQ0-DQ15) are placed in a high-impedance state.

3.3 Standby

CE# at a logic-high level (V_{IH}) places the device in standby mode which substantially reduces device power consumption. DQ0-DQ15 outputs are placed in a high-impedance state independent of OE#. If deselected during block erase or word write, the device continues functioning, and consuming active power until the operation completes.

3.4 Deep Power-Down

RP# at V_{IL} initiates the deep power-down mode.

In read modes, RP#-low deselects the memory, places output drivers in a high-impedance state and turns off all internal circuits. RP# must be held low for a minimum of 100 ns. Time t_{PHQV} is required after return from power-down until initial memory access outputs are valid. After this wake-up interval, normal operation is restored. The CUI is reset to read array mode and status register is set to 80H.

During block erase or word write modes, RP#-low will abort the operation. RY/BY# remains low until the reset operation is complete. Memory contents being altered are no longer valid; the data may be partially erased or written. Time t_{PHWL} is required after RP# goes to logic-high (V_{IH}) before another command can be written.

As with any automated device, it is important to

assert RP# during system reset. When the system comes out of reset, it expects to read from the flash memory. Automated flash memories provide status information when accessed during block erase or word write modes. If a CPU reset occurs with no flash memory reset, proper CPU initialization may not occur because the flash memory may be providing status information instead of array data. SHARP's flash memories allow proper CPU initialization following a system reset through the use of the RP# input. In this application, RP# is controlled by the same RESET# signal that resets the system CPU.

3.5 Read Identifier Codes Operation

The read identifier codes operation outputs the manufacture code and device code (see Fig. 2). Using the manufacture and device codes, the system CPU can automatically match the device with its proper algorithms.

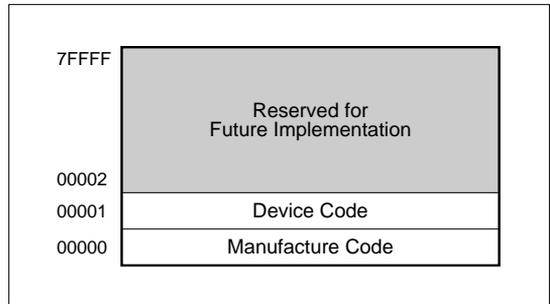


Fig. 2 Device Identifier Code Memory Map

3.6 Write

Writing commands to the CUI enable reading of device data and identifier codes. They also control inspection and clearing of the status register. When V_{CC} = V_{CC1/2/3/4} and V_{PP} = V_{PPH1/2/3}, the CUI additionally controls block erasure and word write.

The Block Erase command requires appropriate command data and an address within the block to be erased. The Word Write command requires the command and address of the location to be written.

The CUI does not occupy an addressable memory location. It is written when WE# and CE# are active. The address and data needed to execute a command are latched on the rising edge of WE# or CE# (whichever goes high first). Standard microprocessor write timings are used. **Fig. 12** and **Fig. 13** illustrate WE# and CE# controlled write operations.

4 COMMAND DEFINITIONS

When the VPP voltage \leq VPPLK, read operations from the status register, identifier codes, or blocks are enabled. Placing VPPH1/2/3 on VPP enables successful block erase and word write operations.

Device operations are selected by writing specific commands into the CUI. **Table 3** defines these commands.

Table 2 Bus Operations

MODE	NOTE	RP#	CE#	OE#	WE#	ADDRESS	VPP	DQ0-15	RY/BY#
Read	1, 2, 3, 8	V _{IH} or V _{HH}	V _{IL}	V _{IL}	V _{IH}	X	X	DOUT	X
Output Disable	3	V _{IH} or V _{HH}	V _{IL}	V _{IH}	V _{IH}	X	X	High Z	X
Standby	3	V _{IH} or V _{HH}	V _{IH}	X	X	X	X	High Z	X
Deep Power-Down	4	V _{IL}	X	X	X	X	X	High Z	V _{OH}
Read Identifier Codes	8	V _{IH} or V _{HH}	V _{IL}	V _{IL}	V _{IH}	See Fig. 2	X	(NOTE 5)	V _{OH}
Write	3, 6, 7, 8	V _{IH} or V _{HH}	V _{IL}	V _{IH}	V _{IL}	X	X	DIN	X

NOTES :

1. Refer to **Section 6.2.3 "DC CHARACTERISTICS"**. When $V_{PP} \leq V_{PPLK}$, memory contents can be read, but not altered.
2. X can be V_{IL} or V_{IH} for control pins and addresses, and VPPLK or VPPH1/2/3 for VPP. See **Section 6.2.3 "DC CHARACTERISTICS"** for VPPLK and VPPH1/2/3 voltages.
3. RY/BY# is V_{OL} when the WSM is executing internal block erase or word write algorithms. It is V_{OH} during when the WSM is not busy, in block erase suspend mode (with word write inactive), word write suspend mode or deep power-down mode.
4. RP# at GND \pm 0.2 V ensures the lowest deep power-down current.
5. See **Section 4.2** for read identifier code data.
6. Command writes involving block erase or word write are reliably executed when $V_{PP} = V_{PPH1/2/3}$ and $V_{CC} = V_{CC1/2/3/4}$. Block erase or word write with $V_{IH} < RP\# < V_{HH}$ produce spurious results and should not be attempted.
7. Refer to **Table 3** for valid DIN during a write operation.
8. Don't use the timing both OE# and WE# are V_{IL}.

Table 3 Command Definitions (NOTE 7)

COMMAND	BUS CYCLES REQ'D.	NOTE	FIRST BUS CYCLE			SECOND BUS CYCLE		
			Oper (NOTE 1)	Addr (NOTE 2)	Data (NOTE 3)	Oper (NOTE 1)	Addr (NOTE 2)	Data (NOTE 3)
Read Array/Reset	1		Write	X	FFH			
Read Identifier Codes	≥ 2	4	Write	X	90H	Read	IA	ID
Read Status Register	2		Write	X	70H	Read	X	SRD
Clear Status Register	1		Write	X	50H			
Block Erase	2	5	Write	BA	20H	Write	BA	D0H
Word Write	2	5, 6	Write	WA	40H or 10H	Write	WA	WD
Block Erase and Word Write Suspend	1	5	Write	X	B0H			
Block Erase and Word Write Resume	1	5	Write	X	D0H			

NOTES :

1. Bus operations are defined in **Table 2**.
2. X = Any valid address within the device.
IA = Identifier code address : see **Fig. 2**.
BA = Address within the block being erased.
WA = Address of memory location to be written.
3. SRD = Data read from status register. See **Table 6** for a description of the status register bits.
WD = Data to be written at location WA. Data is latched on the rising edge of WE# or CE# (whichever goes high first).
ID = Data read from identifier codes.
4. Following the Read Identifier Codes command, read operations access manufacture and device codes. See **Section 4.2** for read identifier code data.
5. If the block is boot block, WP# must be at VIH or RP# must be at VHH to enable block erase or word write operations. Attempts to issue a block erase or word write to a boot block while WP# is VIH or RP# is VIH.
6. Either 40H or 10H is recognized by the WSM as the word write setup.
7. Commands other than those shown above are reserved by SHARP for future device implementations and should not be used.

4.1 Read Array Command

Upon initial device power-up and after exit from deep power-down mode, the device defaults to read array mode. This operation is also initiated by writing the Read Array command. The device remains enabled for reads until another command is written. Once the internal WSM has started a block erase or word write, the device will not recognize the Read Array command until the WSM completes its operation unless the WSM is suspended via an Erase Suspend or Word Write Suspend command. The Read Array command functions independently of the VPP voltage and RP# can be VIH or VHH.

4.2 Read Identifier Codes Command

The identifier code operation is initiated by writing the Read Identifier Codes command. Following the command write, read cycles from addresses shown in **Fig. 2** retrieve the manufacture and device codes (see **Table 4** for identifier code values). To terminate the operation, write another valid command. Like the Read Array command, the Read Identifier Codes command functions independently of the VPP voltage and RP# can be VIH or VHH. Following the Read Identifier Codes command, the following information can be read :

Table 4 Identifier Codes

CODE	ADDRESS	DATA
Manufacture Code	00000H	00B0H
Device Code (Top Boot)	00001H	0060H
Device Code (Bottom Boot)	00001H	0062H

4.3 Read Status Register Command

The status register may be read to determine when a block erase or word write is complete and whether the operation completed successfully. It may be read at any time by writing the Read Status Register command. After writing this command, all subsequent read operations output data from the status register until another valid command is written. The status register contents are latched on

the falling edge of OE# or CE#, whichever occurs. OE# or CE# must toggle to VIH before further reads to update the status register latch. The Read Status Register command functions independently of the VPP voltage. RP# can be VIH or VHH.

4.4 Clear Status Register Command

Status register bits SR.5, SR.4, SR.3 or SR.1 are set to "1"s by the WSM and can only be reset by the Clear Status Register command. These bits indicate various failure conditions (see **Table 6**). By allowing system software to reset these bits, several operations (such as cumulatively erasing multiple blocks or writing several words in sequence) may be performed. The status register may be polled to determine if an error occurred during the sequence.

To clear the status register, the Clear Status Register command (50H) is written. It functions independently of the applied VPP voltage. RP# can be VIH or VHH. This command is not functional during block erase or word write suspend modes.

4.5 Block Erase Command

Erase is executed one block at a time and initiated by a two-cycle command. A block erase setup is first written, followed by a block erase confirm. This command sequence requires appropriate sequencing and an address within the block to be erased (erase changes all block data to FFFFH). Block preconditioning, erase, and verify are handled internally by the WSM (invisible to the system). After the two-cycle block erase sequence is written, the device automatically outputs status register data when read (see **Fig. 3**). The CPU can detect block erase completion by analyzing the output data of the RY/BY# pin or status register bit SR.7.

When the block erase is complete, status register bit SR.5 should be checked. If a block erase error is detected, the status register should be cleared before system software attempts corrective actions.

The CUI remains in read status register mode until a new command is issued.

This two-step command sequence of set-up followed by execution ensures that block contents are not accidentally erased. An invalid Block Erase command sequence will result in both status register bits SR.4 and SR.5 being set to "1". Also, reliable block erasure can only occur when $V_{CC} = V_{CC1/2/3/4}$ and $V_{PP} = V_{PPH1/2/3}$. In the absence of this high voltage, block contents are protected against erasure. If block erase is attempted while $V_{PP} \leq V_{PPLK}$, SR.3 and SR.5 will be set to "1". Successful block erase for boot blocks requires that the corresponding if set, that $WP\# = V_{IH}$ or $RP\# = V_{HH}$. If block erase is attempted to boot block when the corresponding $WP\# = V_{IL}$ or $RP\# = V_{IH}$, SR.1 and SR.5 will be set to "1". Block erase operations with $V_{IH} < RP\# < V_{HH}$ produce spurious results and should not be attempted.

4.6 Word Write Command

Word write is executed by a two-cycle command sequence. Word write setup (standard 40H or alternate 10H) is written, followed by a second write that specifies the address and data (latched on the rising edge of WE#). The WSM then takes over, controlling the word write and write verify algorithms internally. After the word write sequence is written, the device automatically outputs status register data when read (see **Fig. 4**). The CPU can detect the completion of the word write event by analyzing the RY/BY# pin or status register bit SR.7.

When word write is complete, status register bit SR.4 should be checked. If word write error is detected, the status register should be cleared. The internal WSM verify only detects errors for "1"s that do not successfully write to "0"s. The CUI remains in read status register mode until it receives another command.

Reliable word writes can only occur when $V_{CC} = V_{CC1/2/3/4}$ and $V_{PP} = V_{PPH1/2/3}$. In the absence of this high voltage, memory contents are protected against word writes. If word write is attempted while $V_{PP} \leq V_{PPLK}$, status register bits SR.3 and SR.4 will be set to "1". Successful word write for boot blocks requires that the corresponding if set, that $WP\# = V_{IH}$ or $RP\# = V_{HH}$. If word write is attempted to boot block when the corresponding $WP\# = V_{IL}$ or $RP\# = V_{IH}$, SR.1 and SR.4 will be set to "1". Word write operations with $V_{IH} < RP\# < V_{HH}$ produce spurious results and should not be attempted.

4.7 Block Erase Suspend Command

The Block Erase Suspend command allows block erase interruption to read or word write data in another block of memory. Once the block erase process starts, writing the Block Erase Suspend command requests that the WSM suspend the block erase sequence at a predetermined point in the algorithm. The device outputs status register data when read after the Block Erase Suspend command is written. Polling status register bits SR.7 and SR.6 can determine when the block erase operation has been suspended (both will be set to "1"). RY/BY# will also transition to V_{OH} . Specification t_{WHRH2} defines the block erase suspend latency.

At this point, a Read Array command can be written to read data from blocks other than that which is suspended. A Word Write command sequence can also be issued during erase suspend to program data in other blocks. Using the Word Write Suspend command (see **Section 4.8**), a word write operation can also be suspended. During a word write operation with block erase suspended, status register bit SR.7 will return to "0" and the RY/BY# output will transition to V_{OL} . However, SR.6 will remain "1" to indicate block erase suspend status.

The only other valid commands while block erase is suspended are Read Status Register and Block Erase Resume. After a Block Erase Resume command is written to the flash memory, the WSM will continue the block erase process. Status register bits SR.6 and SR.7 will automatically clear and RY/BY# will return to VOL. After the Erase Resume command is written, the device automatically outputs status register data when read (see **Fig. 5**). VPP must remain at VPPH1/2/3 (the same VPP level used for block erase) while block erase is suspended. RP# must also remain at VIH or VHH (the same RP# level used for block erase). WP# must also remain at VIL or VIH (the same WP# level used for block erase). Block erase cannot resume until word write operations initiated during block erase suspend have completed.

4.8 Word Write Suspend Command

The Word Write Suspend command allows word write interruption to read data in other flash memory locations. Once the word write process starts, writing the Word Write Suspend command requests that the WSM suspend the word write sequence at a predetermined point in the algorithm. The device continues to output status register data when read after the Word Write Suspend command is written. Polling status register bits SR.7 and SR.2 can determine when the word write operation has been suspended (both will be set to "1"). RY/BY# will also transition to VOH. Specification tWHRH1 defines the word write suspend latency.

At this point, a Read Array command can be written to read data from locations other than that which is suspended. The only other valid commands while word write is suspended are Read Status Register and Word Write Resume. After Word Write Resume command is written to the flash memory, the WSM will continue the word write process. Status register bits SR.2 and SR.7 will automatically clear and RY/BY# will return to VOL. After the Word Write Resume command is

written, the device automatically outputs status register data when read (see **Fig. 6**). VPP must remain at VPPH1/2/3 (the same VPP level used for word write) while in word write suspend mode. RP# must also remain at VIH or VHH (the same RP# level used for word write). WP# must also remain at VIL or VIH (the same WP# level used for word write).

4.9 Block Locking

This Boot Block flash memory architecture features two hardware-lockable boot blocks so that the kernel code for the system can be kept secure while other blocks are programmed or erased as necessary.

4.9.1 VPP = VIL FOR COMPLETE PROTECTION

The VPP programming voltage can be held low for complete write protection of all blocks in the flash device.

4.9.2 WP# = VIL FOR BLOCK LOCKING

The lockable blocks are locked when WP# = VIL; any program or erase operation to a locked block will result in an error, which will be reflected in the status register. For top configuration, the top two boot blocks are lockable. For the bottom configuration, the bottom two boot blocks are lockable. Unlocked blocks can be programmed or erased normally (Unless VPP is below VPPLK).

4.9.3 BLOCK UNLOCKING

WP# = VIH or RP# = VHH unlocks all lockable blocks.

These blocks can now be programmed or erased.

WP# or RP# controls all block locking and VPP provides protection against spurious writes. **Table 5** defines the write protection methods.

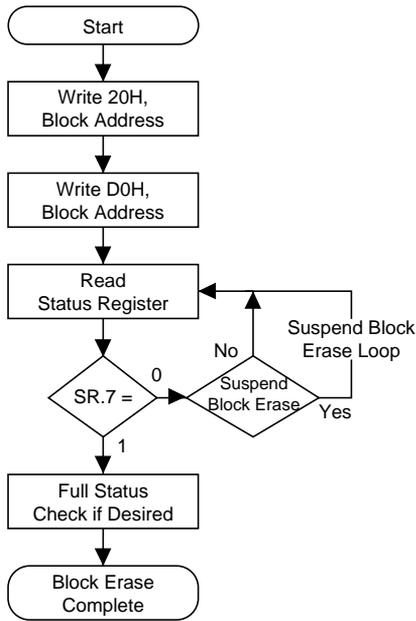
Table 5 Write Protection Alternatives

OPERATION	VPP	RP#	WP#	EFFECT
Block Erase or Word Write	VIL	X	X	All Blocks Locked.
	> VPP _{LK}	VIL	X	All Blocks Locked.
		VHH	X	All Blocks Unlocked.
		VIH	VIL	2 Boot Blocks Locked.
			VIH	All Blocks Unlocked.

Table 6 Status Register Definition

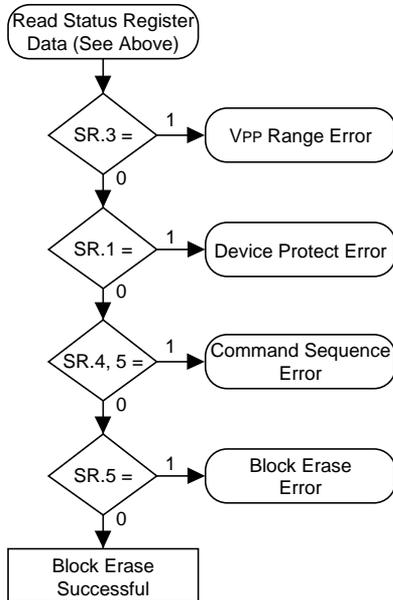
WSMS	ESS	ES	WWS	VPPS	WWSS	DPS	R
7	6	5	4	3	2	1	0

<p>SR.7 = WRITE STATE MACHINE STATUS (WSMS) 1 = Ready 0 = Busy</p> <p>SR.6 = ERASE SUSPEND STATUS (ESS) 1 = Block Erase Suspended 0 = Block Erase in Progress/Completed</p> <p>SR.5 = ERASE STATUS (ES) 1 = Error in Block Erase 0 = Successful Block Erase</p> <p>SR.4 = WORD WRITE STATUS (WWS) 1 = Error in Word Write 0 = Successful Word Write</p> <p>SR.3 = VPP STATUS (VPPS) 1 = VPP Low Detect, Operation Abort 0 = VPP OK</p> <p>SR.2 = WORD WRITE SUSPEND STATUS (WWSS) 1 = Word Write Suspended 0 = Word Write in Progress/Completed</p> <p>SR.1 = DEVICE PROTECT STATUS (DPS) 1 = WP# or RP# Lock Detected, Operation Abort 0 = Unlock</p> <p>SR.0 = RESERVED FOR FUTURE ENHANCEMENTS (R)</p>	<p>NOTES :</p> <p>Check RY/BY# or SR.7 to determine block erase or word write completion. SR.6-0 are invalid while SR.7 = "0".</p> <p>If both SR.5 and SR.4 are "1"s after a block erase attempt, an improper command sequence was entered.</p> <p>SR.3 does not provide a continuous indication of VPP level. The WSM interrogates and indicates the VPP level only after Block Erase or Word Write command sequences. SR.3 is not guaranteed to reports accurate feedback only when $VPP \neq VPPH1/2/3$.</p> <p>The WSM interrogates the WP# and RP# only after Block Erase or Word Write command sequences. It informs the system, depending on the attempted operation, if the WP# is not VIH, RP# is not VHH.</p> <p>SR.0 is reserved for future use and should be masked out when polling the status register.</p>
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BUS OPERATION	COMMAND	COMMENTS
Write	Erase Setup	Data = 20H Addr = Within Block to be Erased
Write	Erase Confirm	Data = D0H Addr = Within Block to be Erased
Read		Status Register Data
Standby		Check SR.7 1 = WSM Ready 0 = WSM Busy
Repeat for subsequent block erasures.		
Full status check can be done after each block erase or after a sequence of block erasures.		
Write FFH after the last block erase operation to place device in read array mode.		

FULL STATUS CHECK PROCEDURE



BUS OPERATION	COMMAND	COMMENTS
Standby		Check SR.3 1 = VPP Error Detect
Standby		Check SR.1 1 = Device Protect Detect
Standby		Check SR.4, 5 Both 1 = Command Sequence Error
Standby		Check SR.5 1 = Block Erase Error
SR.5, SR.4, SR.3 and SR.1 are only cleared by the Clear Status Register command in cases where multiple blocks are erased before full status is checked.		
If error is detected, clear the status register before attempting retry or other error recovery.		

Fig. 3 Automated Block Erase Flowchart

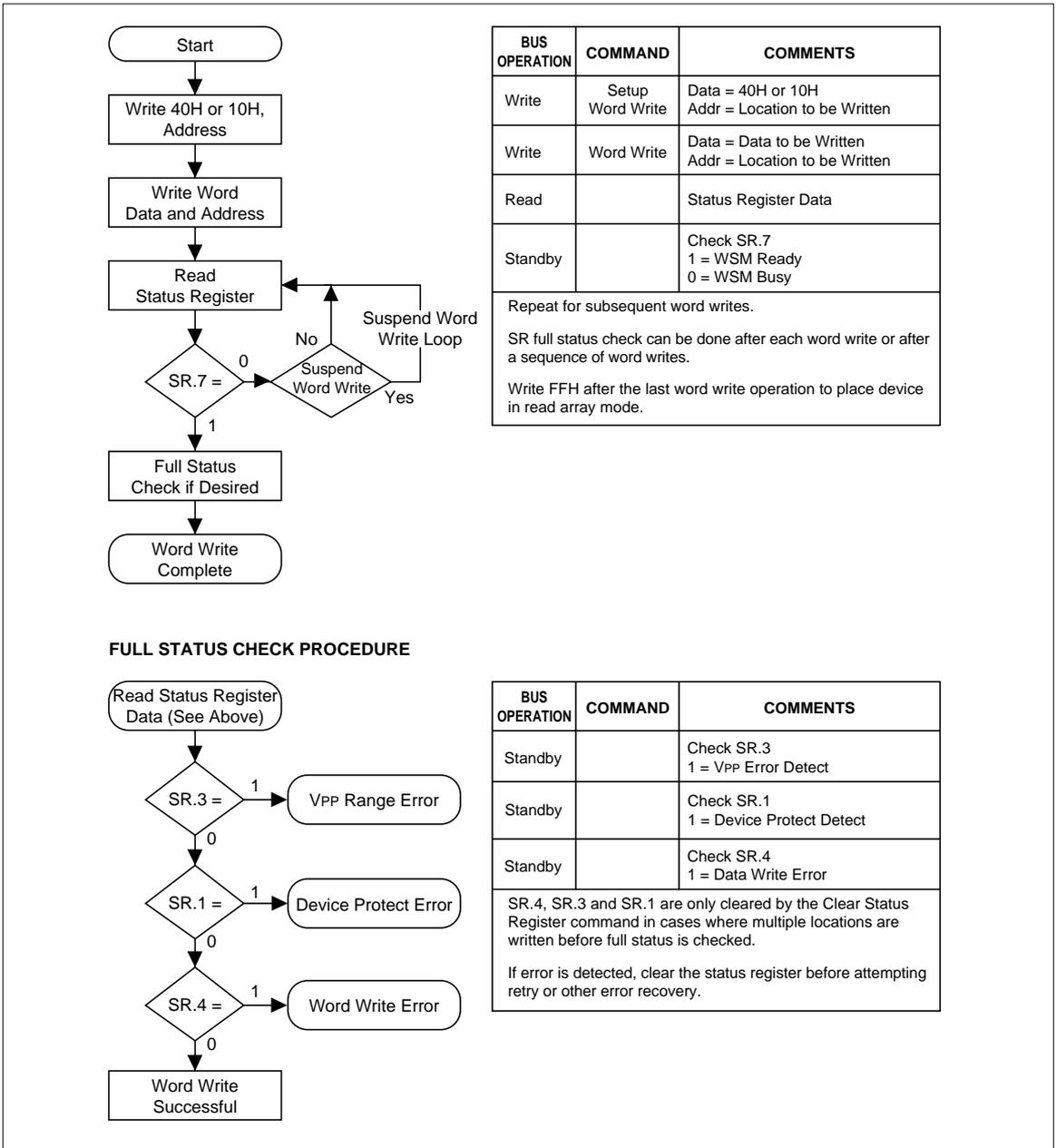


Fig. 4 Automated Word Write Flowchart

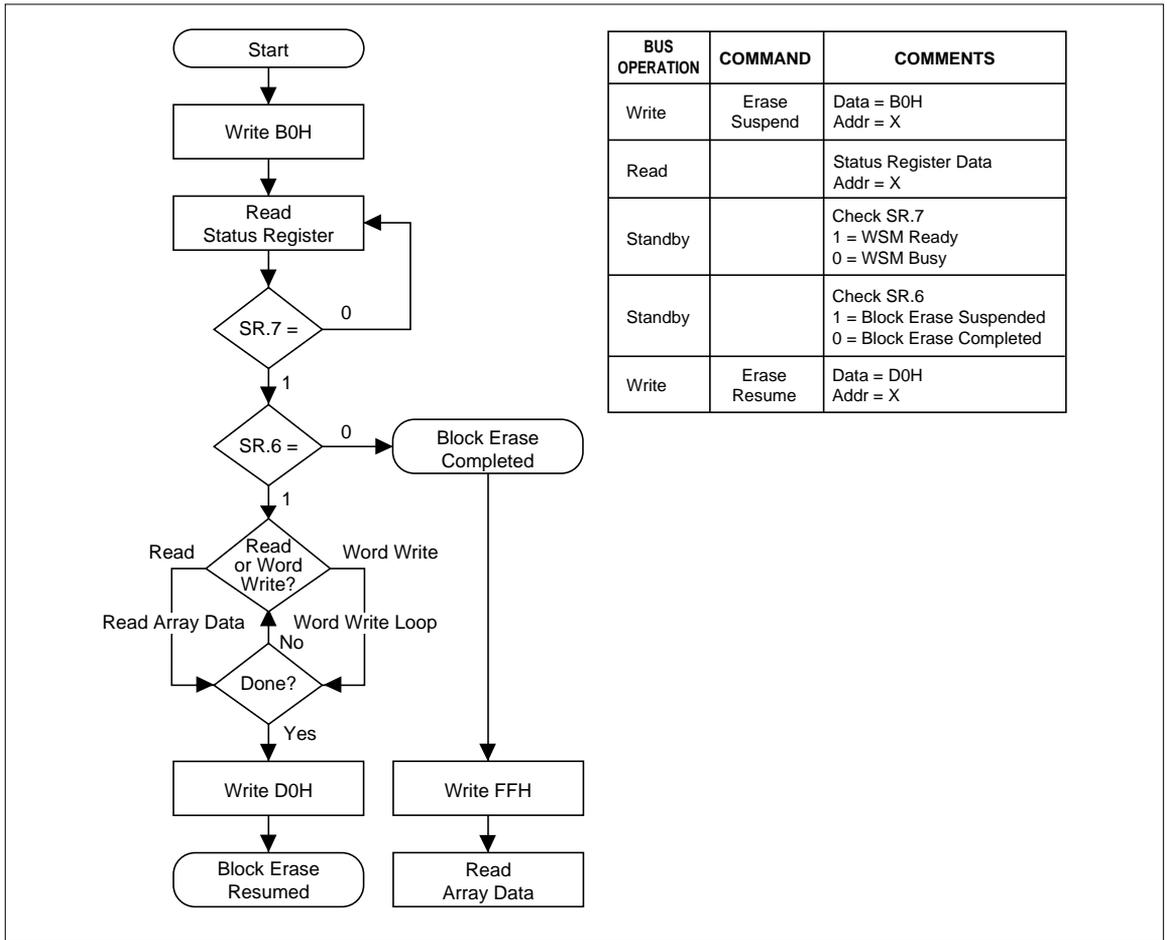
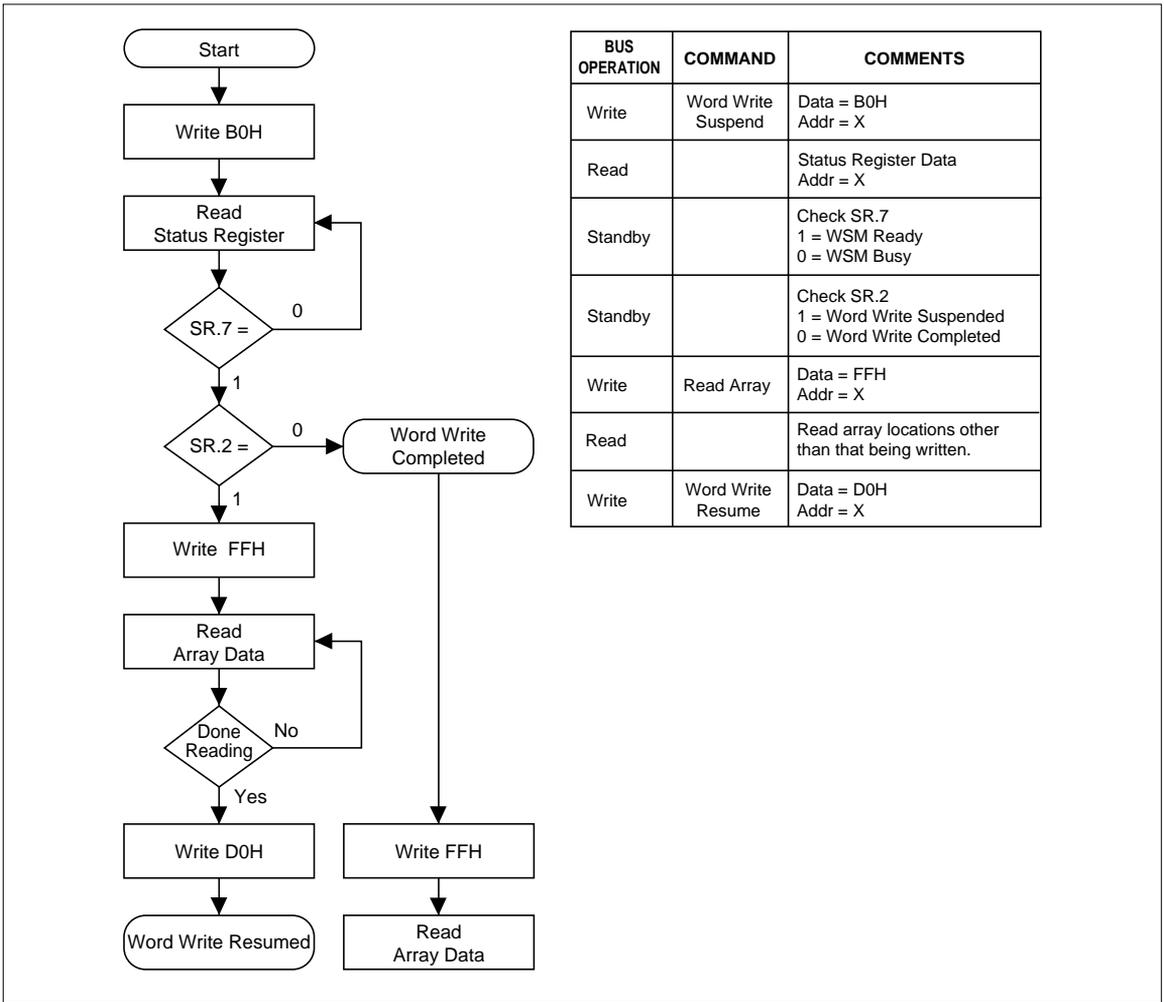


Fig. 5 Block Erase Suspend/Resume Flowchart



BUS OPERATION	COMMAND	COMMENTS
Write	Word Write Suspend	Data = B0H Addr = X
Read		Status Register Data Addr = X
Standby		Check SR.7 1 = WSM Ready 0 = WSM Busy
Standby		Check SR.2 1 = Word Write Suspended 0 = Word Write Completed
Write	Read Array	Data = FFH Addr = X
Read		Read array locations other than that being written.
Write	Word Write Resume	Data = D0H Addr = X

Fig. 6 Word Write Suspend/Resume Flowchart

5 DESIGN CONSIDERATIONS

5.1 Three-Line Output Control

The device will often be used in large memory arrays. SHARP provides three control inputs to accommodate multiple memory connections. Three-line control provides for :

- a. Lowest possible memory power consumption.
- b. Complete assurance that data bus contention will not occur.

To use these control inputs efficiently, an address decoder should enable CE# while OE# should be connected to all memory devices and the system's READ# control line. This assures that only selected memory devices have active outputs while deselected memory devices are in standby mode. RP# should be connected to the system POWERGOOD signal to prevent unintended writes during system power transitions. POWERGOOD should also toggle during system reset.

5.2 RY/BY#, Block Erase and Word Write Polling

RY/BY# is a full CMOS output that provides a hardware method of detecting block erase and word write completion. It transitions low after block erase or word write commands and returns to V_{OH} when the WSM has finished executing the internal algorithm.

RY/BY# can be connected to an interrupt input of the system CPU or controller. It is active at all times. RY/BY# is also V_{OH} when the device is in block erase suspend (with word write inactive), word write suspend or deep power-down modes.

5.3 Power Supply Decoupling

Flash memory power switching characteristics require careful device decoupling. System designers are interested in three supply current issues; standby current levels, active current levels

and transient peaks produced by falling and rising edges of CE# and OE#. Transient current magnitudes depend on the device outputs' capacitive and inductive loading. Two-line control and proper decoupling capacitor selection will suppress transient voltage peaks. Each device should have a 0.1 μF ceramic capacitor connected between its VCC and GND and between its VPP and GND. These high-frequency, low inductance capacitors should be placed as close as possible to package leads. Additionally, for every eight devices, a 4.7 μF electrolytic capacitor should be placed at the array's power supply connection between VCC and GND. The bulk capacitor will overcome voltage slumps caused by PC board trace inductance.

5.4 VPP Trace on Printed Circuit Boards

Updating flash memories that reside in the target system requires that the printed circuit board designers pay attention to the VPP power supply trace. The VPP pin supplies the memory cell current for word writing and block erasing. Use similar trace widths and layout considerations given to the VCC power bus. Adequate VPP supply traces and decoupling will decrease VPP voltage spikes and overshoots.

5.5 VCC, VPP, RP# Transitions

Block erase and word write are not guaranteed if VPP falls outside of a valid $V_{PPH1/2/3}$ range, VCC falls outside of a valid $V_{CC1/2/3/4}$ range, or $RP\# \neq V_{IH}$ or V_{HH} . If VPP error is detected, status register bit SR.3 is set to "1" along with SR.4 or SR.5, depending on the attempted operation. If RP# transitions to V_{IL} during block erase or word write, RY/BY# will remain low until the reset operation is complete. Then, the operation will abort and the device will enter deep power-down. The aborted operation may leave data partially altered. Therefore, the command sequence must be repeated after normal operation is restored. Device power-off or RP# transitions to V_{IL} clear the status register.

The CUI latches commands issued by system software and is not altered by V_{PP} or $CE\#$ transitions or WSM actions. Its state is read array mode upon power-up, after exit from deep power-down or after V_{CC} transitions below V_{LKO} .

After block erase or word write, even after V_{PP} transitions down to V_{PPLK} , the CUI must be placed in read array mode via the Read Array command if subsequent access to the memory array is desired.

5.6 Power-Up/Down Protection

The device is designed to offer protection against accidental block erasure or word writing during power transitions. Upon power-up, the device is indifferent as to which power supply (V_{PP} or V_{CC}) powers-up first. Internal circuitry resets the CUI to read array mode at power-up.

A system designer must guard against spurious writes for V_{CC} voltages above V_{LKO} when V_{PP} is active. Since both $WE\#$ and $CE\#$ must be low for a command write, driving either to V_{IH} will inhibit writes. The CUI's two-step command sequence architecture provides added level of protection against data alteration.

$WP\#$ provides additional protection from inadvertent code or data alteration. The device is disabled while $RP\# = V_{IL}$ regardless of its control inputs state.

5.7 Power Consumption

When designing portable systems, designers must consider battery power consumption not only during device operation, but also for data retention during system idle time. Flash memory's nonvolatility increases usable battery life because data is retained when system power is removed.

In addition, deep power-down mode ensures extremely low power consumption even when system power is applied. For example, portable computing products and other power sensitive applications that use an array of devices for solid-state storage can consume negligible power by lowering $RP\#$ to V_{IL} standby or sleep modes. If access is again needed, the devices can be read following the t_{PHQV} and t_{PHWL} wake-up cycles required after $RP\#$ is first raised to V_{IH} . See **Section 6.2.4 through 6.2.6 "AC CHARACTERISTICS - READ-ONLY and WRITE OPERATIONS"** and **Fig. 11, Fig. 12 and Fig.13** for more information.

6 ELECTRICAL SPECIFICATIONS

6.1 Absolute Maximum Ratings*

Operating Temperature

- LH28F800BG-L

During Read, Block Erase and
Word Write 0 to +70°C (NOTE 1)
Temperature under Bias -10 to +80°C

- LH28F800BGH-L

During Read, Block Erase and
Word Write -40 to +85°C (NOTE 2)
Temperature under Bias -40 to +85°C

Storage Temperature -65 to +125°C

Voltage On Any Pin

(except V_{CC}, V_{PP}, and RP#) -2.0 to +7.0 V (NOTE 3)

V_{CC} Supply Voltage -2.0 to +7.0 V (NOTE 3)

V_{PP} Update Voltage during
Block Erase and

Word Write -2.0 to +14.0 V (NOTE 3, 4)

RP# Voltage -2.0 to +14.0 V (NOTE 3, 4)

Output Short Circuit Current 100 mA (NOTE 5)

6.2 Operating Conditions

SYMBOL	PARAMETER	NOTE	MIN.	MAX.	UNIT	VERSIONS
T _A	Operating Temperature	1	0	+70	°C	LH28F800BG-L
			-40	+85	°C	LH28F800BGH-L
V _{CC1}	V _{CC} Supply Voltage (2.7 to 3.6 V)		2.7	3.6	V	
V _{CC2}	V _{CC} Supply Voltage (3.3±0.3 V)		3.0	3.6	V	
V _{CC3}	V _{CC} Supply Voltage (5.0±0.25 V)		4.75	5.25	V	LH28F800BG-L85/BGH-L85
V _{CC4}	V _{CC} Supply Voltage (5.0±0.5 V)		4.50	5.50	V	

NOTE :

1. Test condition : Ambient temperature

NOTICE : The specifications are subject to change without notice. Verify with your local SHARP sales office that you have the latest datasheet before finalizing a design.

* **WARNING** : *Stressing the device beyond the "Absolute Maximum Ratings" may cause permanent damage. These are stress ratings only. Operation beyond the "Operating Conditions" is not recommended and extended exposure beyond the "Operating Conditions" may affect device reliability.*

NOTES :

1. Operating temperature is for commercial product defined by this specification.
2. Operating temperature is for extended temperature product defined by this specification.
3. All specified voltages are with respect to GND. Minimum DC voltage is -0.5 V on input/output pins and -0.2 V on V_{CC} and V_{PP} pins. During transitions, this level may undershoot to -2.0 V for periods < 20 ns. Maximum DC voltage on input/output pins and V_{CC} is V_{CC}+0.5 V which, during transitions, may overshoot to V_{CC}+2.0 V for periods < 20 ns.
4. Maximum DC voltage on V_{PP} and RP# may overshoot to +14.0 V for periods < 20 ns.
5. Output shorted for no more than one second. No more than one output shorted at a time.

6.2.1 CAPACITANCE (NOTE 1)

T_A = +25°C, f = 1 MHz

SYMBOL	PARAMETER	TYP.	MAX.	UNIT	CONDITION
C _{IN}	Input Capacitance	7	10	pF	V _{IN} = 0.0 V
C _{OUT}	Output Capacitance	9	12	pF	V _{OUT} = 0.0 V

NOTE :

1. Sampled, not 100% tested.

6.2.2 AC INPUT/OUTPUT TEST CONDITIONS

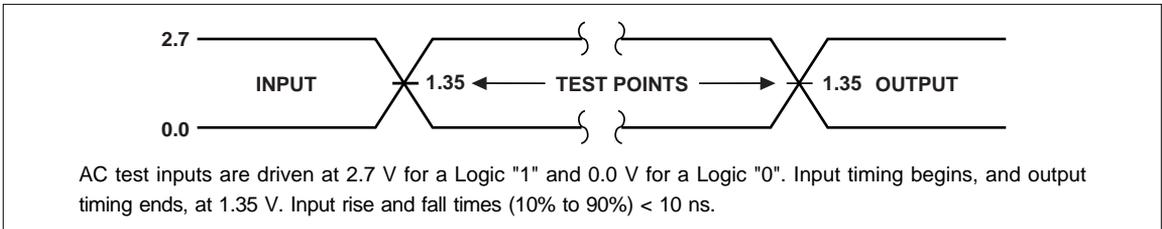


Fig. 7 Transient Input/Output Reference Waveform for V_{CC} = 2.7 to 3.6 V

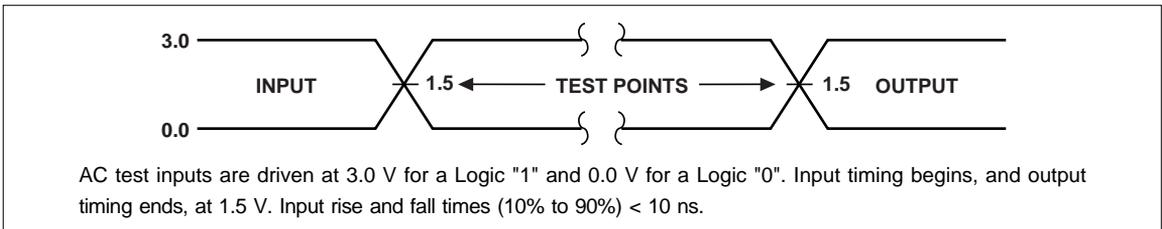


Fig. 8 Transient Input/Output Reference Waveform for V_{CC} = 3.3±0.3 V and V_{CC} = 5.0±0.25 V (High Speed Testing Configuration)

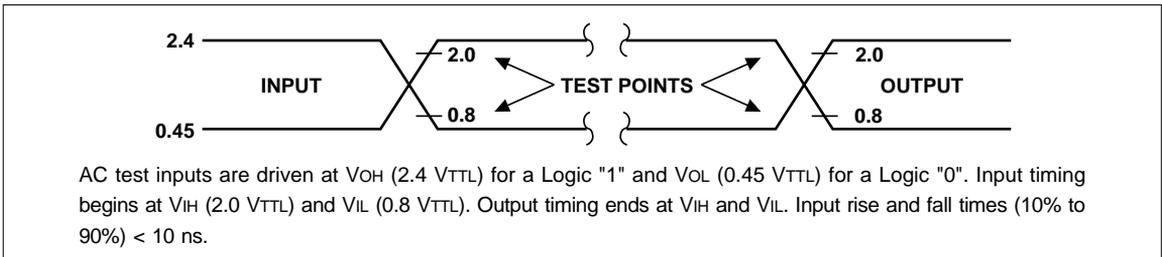


Fig. 9 Transient Input/Output Reference Waveform for V_{CC} = 5.0±0.5 V (Standard Testing Configuration)

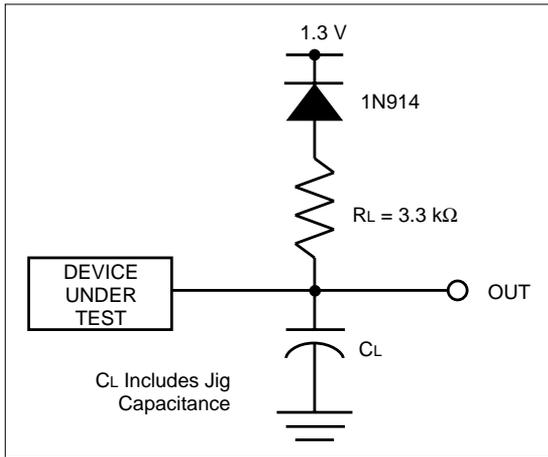


Fig. 10 Transient Equivalent Testing Load Circuit

Test Configuration Capacitance Loading Value

TEST CONFIGURATION	CL (pF)
$V_{CC} = 3.3 \pm 0.3\text{ V}$, 2.7 to 3.6 V	50
$V_{CC} = 5.0 \pm 0.25\text{ V}$ (NOTE 1)	30
$V_{CC} = 5.0 \pm 0.5\text{ V}$	100

NOTE :

1. Applied to high-speed products, LH28F800BG-L85 and LH28F800BGH-L85.

6.2.3 DC CHARACTERISTICS

SYMBOL	PARAMETER		NOTE	V _{CC} = 2.7 to 3.6 V		V _{CC} = 5.0±0.5 V		UNIT	TEST CONDITIONS
				TYP.	MAX.	TYP.	MAX.		
I _{LI}	Input Load Current		1		±0.5		±1	μA	V _{CC} = V _{CC} Max. V _{IN} = V _{CC} or GND
I _{LO}	Output Leakage Current		1		±0.5		±10	μA	V _{CC} = V _{CC} Max. V _{OUT} = V _{CC} or GND
I _{CCS}	V _{CC} Standby Current		1, 3, 6	25	50	30	100	μA	CMOS Inputs V _{CC} = V _{CC} Max. CE# = RP# = V _{CC} ±0.2 V
				0.2	2	0.4	2	mA	TTL Inputs V _{CC} = V _{CC} Max. CE# = RP# = V _{IH}
I _{CCD}	V _{CC} Deep Power-Down Current	LH28F800BG-L	1	4	10		10	μA	RP# = GND±0.2 V I _{OUT} (RY/BY#) = 0 mA
		LH28F800BGH-L		4	20		20		
I _{CCR}	V _{CC} Read Current		1, 5, 6	15	25		50	mA	CMOS Inputs V _{CC} = V _{CC} Max. CE# = GND f = 5 MHz (3.3 V, 2.7 V), 8 MHz (5 V) I _{OUT} = 0 mA
					30		65	mA	TTL Inputs V _{CC} = V _{CC} Max. CE# = GND f = 5 MHz (3.3 V, 2.7 V), 8 MHz (5 V) I _{OUT} = 0 mA
I _{CCW}	V _{CC} Word Write Current		1, 7	5	17	—	—	mA	V _{PP} = 2.7 to 3.6 V
				5	17		35	mA	V _{PP} = 5.0±0.5 V
				5	12		30	mA	V _{PP} = 12.0±0.6 V
I _{CCB}	V _{CC} Block Erase Current		1, 7	4	17	—	—	mA	V _{PP} = 2.7 to 3.6 V
				4	17		30	mA	V _{PP} = 5.0±0.5 V
				4	12		25	mA	V _{PP} = 12.0±0.6 V
I _{CCWS} I _{CCES}	V _{CC} Word Write or Block Erase Suspend Current		1, 2	1	6	1	10	mA	CE# = V _{IH}
I _{PPS} I _{PPR}	V _{PP} Standby or Read Current		1	±2	±15	±2	±15	μA	V _{PP} ≤ V _{CC}
				10	200	10	200	μA	V _{PP} > V _{CC}
I _{PPD}	V _{PP} Deep Power-Down Current		1	0.1	5	0.1	5	μA	RP# = GND±0.2 V
I _{PPW}	V _{PP} Word Write Current		1, 7	12	40	—	—	mA	V _{PP} = 2.7 to 3.6 V
					40		40	mA	V _{PP} = 5.0±0.5 V
					30		30	mA	V _{PP} = 12.0±0.6 V
I _{PPE}	V _{PP} Block Erase Current		1, 7	8	25	—	—	mA	V _{PP} = 2.7 to 3.6 V
					25		25	mA	V _{PP} = 5.0±0.5 V
					20		20	mA	V _{PP} = 12.0±0.6 V
I _{PPWS} I _{PPES}	V _{PP} Word Write or Block Erase Suspend Current		1	10	200	10	200	μA	V _{PP} = V _{PPH1/2/3}

6.2.3 DC CHARACTERISTICS (contd.)

SYMBOL	PARAMETER	NOTE	V _{CC} = 2.7 to 3.6 V		V _{CC} = 5.0±0.5 V		UNIT	TEST CONDITIONS
			MIN.	MAX.	MIN.	MAX.		
V _{IL}	Input Low Voltage	7	-0.5	0.8	-0.5	0.8	V	
V _{IH}	Input High Voltage	7	2.0	V _{CC} +0.5	2.0	V _{CC} +0.5	V	
V _{OL}	Output Low Voltage	3, 7		0.4		0.45	V	V _{CC} = V _{CC} Min. I _{OL} = 5.8 mA (5 V) I _{OL} = 2.0 mA (3.3 V, 2.7 V)
V _{OH1}	Output High Voltage (TTL)	3, 7	2.4		2.4		V	V _{CC} = V _{CC} Min. I _{OH} = -2.5 mA (5 V) I _{OH} = -2.0 mA (3.3 V, 2.7 V)
V _{OH2}	Output High Voltage (CMOS)	3, 7	0.85		0.85		V	V _{CC} = V _{CC} Min. I _{OH} = -2.5 mA
			V _{CC}		V _{CC}		V	V _{CC} = V _{CC} Min. I _{OH} = -100 µA
V _{PPLK}	V _{PP} Lockout Voltage during Normal Operations	4, 7		1.5		1.5	V	
V _{PPH1}	V _{PP} Voltage during Word Write or Block Erase Operations		2.7	3.6	—	—	V	
V _{PPH2}	V _{PP} Voltage during Word Write or Block Erase Operations		4.5	5.5	4.5	5.5	V	
V _{PPH3}	V _{PP} Voltage during Word Write or Block Erase Operations		11.4	12.6	11.4	12.6	V	
V _{LKO}	V _{CC} Lockout Voltage		2.0		2.0		V	
V _{HH}	RP# Unlock Voltage	8, 9	11.4	12.6	11.4	12.6	V	Unavailable WP#

NOTES :

- All currents are in RMS unless otherwise noted. Typical values at nominal V_{CC} voltage and T_A = +25°C. These currents are valid for all product versions (packages and speeds).
- ICCWS and ICCES are specified with the device deselected. If reading or word writing in erase suspend mode, the device's current draw is the sum of ICCWS or ICCES and ICCR or ICCW, respectively.
- Includes RY/BY#.
- Block erases and word writes are inhibited when V_{PP} ≤ V_{PPLK}, and not guaranteed in the range between V_{PPLK} (max.) and V_{PPH1} (min.), between V_{PPH1} (max.) and V_{PPH2} (min.), between V_{PPH2} (max.) and V_{PPH3} (min.), and above V_{PPH3} (max.).
- Automatic Power Saving (APS) reduces typical ICCR to 1 mA at 5 V V_{CC} and 3 mA at 2.7 V and 3.3 V V_{CC} in static operation.
- CMOS inputs are either V_{CC}±0.2 V or GND±0.2 V. TTL inputs are either V_{IL} or V_{IH}.
- Sampled, not 100% tested.
- Boot block erases and word writes are inhibited when the corresponding RP# = V_{IH} or WP# = V_{IL}. Block erase and word write operations are not guaranteed with V_{IH} < RP# < V_{HH} and should not be attempted.
- RP# connection to a V_{HH} supply is allowed for a maximum cumulative period of 80 hours.

6.2.4 AC CHARACTERISTICS - READ-ONLY OPERATIONS (NOTE 1)

• Vcc = 2.7 to 3.6 V, TA = 0 to +70°C or -40 to +85°C

VERSIONS			LH28F800BG-L85 LH28F800BGH-L85		LH28F800BG-L12 LH28F800BGH-L12		UNIT
SYMBOL	PARAMETER	NOTE	MIN.	MAX.	MIN.	MAX.	
tAVAV	Read Cycle Time		120		150		ns
tAVQV	Address to Output Delay			120		150	ns
tELQV	CE# to Output Delay	2		120		150	ns
tPHQV	RP# High to Output Delay			600		600	ns
tGLQV	OE# to Output Delay	2		50		55	ns
tELQX	CE# to Output in Low Z	3	0		0		ns
tEHQZ	CE# High to Output in High Z	3		55		55	ns
tGLQX	OE# to Output in Low Z	3	0		0		ns
tGHQZ	OE# High to Output in High Z	3		20		25	ns
tOH	Output Hold from Address, CE# or OE# Change, Whichever Occurs First	3	0		0		ns

• Vcc = 3.3±0.3 V, TA = 0 to +70°C or -40 to +85°C

VERSIONS			LH28F800BG-L85 LH28F800BGH-L85		LH28F800BG-L12 LH28F800BGH-L12		UNIT
SYMBOL	PARAMETER	NOTE	MIN.	MAX.	MIN.	MAX.	
tAVAV	Read Cycle Time		100		130		ns
tAVQV	Address to Output Delay			100		130	ns
tELQV	CE# to Output Delay	2		100		130	ns
tPHQV	RP# High to Output Delay			600		600	ns
tGLQV	OE# to Output Delay	2		50		55	ns
tELQX	CE# to Output in Low Z	3	0		0		ns
tEHQZ	CE# High to Output in High Z	3		55		55	ns
tGLQX	OE# to Output in Low Z	3	0		0		ns
tGHQZ	OE# High to Output in High Z	3		20		25	ns
tOH	Output Hold from Address, CE# or OE# Change, Whichever Occurs First	3	0		0		ns

NOTES :

1. See AC Input/Output Reference Waveform (Fig. 7 through Fig. 9) for maximum allowable input slew rate.
2. OE# may be delayed up to tELQV-tGLQV after the falling edge of CE# without impact on tELQV.
3. Sampled, not 100% tested.

6.2.4 AC CHARACTERISTICS - READ-ONLY OPERATIONS (contd.) (NOTE 1)

• $V_{CC} = 5.0 \pm 0.25 \text{ V}$, $5.0 \pm 0.5 \text{ V}$, $T_A = 0 \text{ to } +70^\circ\text{C}$ or $-40 \text{ to } +85^\circ\text{C}$

VERSIONS		$V_{CC} \pm 0.25 \text{ V}$	(NOTE 4) LH28F800BG-L85 LH28F800BGH-L85		(NOTE 5) LH28F800BG-L85 LH28F800BGH-L85		(NOTE 5) LH28F800BG-L12 LH28F800BGH-L12		UNIT
			$V_{CC} \pm 0.5 \text{ V}$		MIN.	MAX.	MIN.	MAX.	
SYMBOL	PARAMETER	NOTE	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
tAVAV	Read Cycle Time		85		90		120		ns
tAVQV	Address to Output Delay			85		90		120	ns
tELQV	CE# to Output Delay	2		85		90		120	ns
tPHQV	RP# High to Output Delay			400		400		400	ns
tGLQV	OE# to Output Delay	2		40		45		50	ns
tELQX	CE# to Output in Low Z	3	0		0		0		ns
tEHQZ	CE# High to Output in High Z	3		55		55		55	ns
tGLQX	OE# to Output in Low Z	3	0		0		0		ns
tGHQZ	OE# High to Output in High Z	3		10		10		15	ns
tOH	Output Hold from Address, CE# or OE# Change, Whichever Occurs First	3	0		0		0		ns

NOTES :

1. See AC Input/Output Reference Waveform (Fig. 7 through Fig. 9) for maximum allowable input slew rate.
2. OE# may be delayed up to tELQV-tGLQV after the falling edge of CE# without impact on tELQV.
3. Sampled, not 100% tested.
4. See Fig. 8 "Transient Input/Output Reference Waveform" and Fig. 10 "Transient Equivalent Testing Load Circuit" (High Speed Configuration) for testing characteristics.
5. See Fig. 9 "Transient Input/Output Reference Waveform" and Fig. 10 "Transient Equivalent Testing Load Circuit" (Standard Configuration) for testing characteristics.

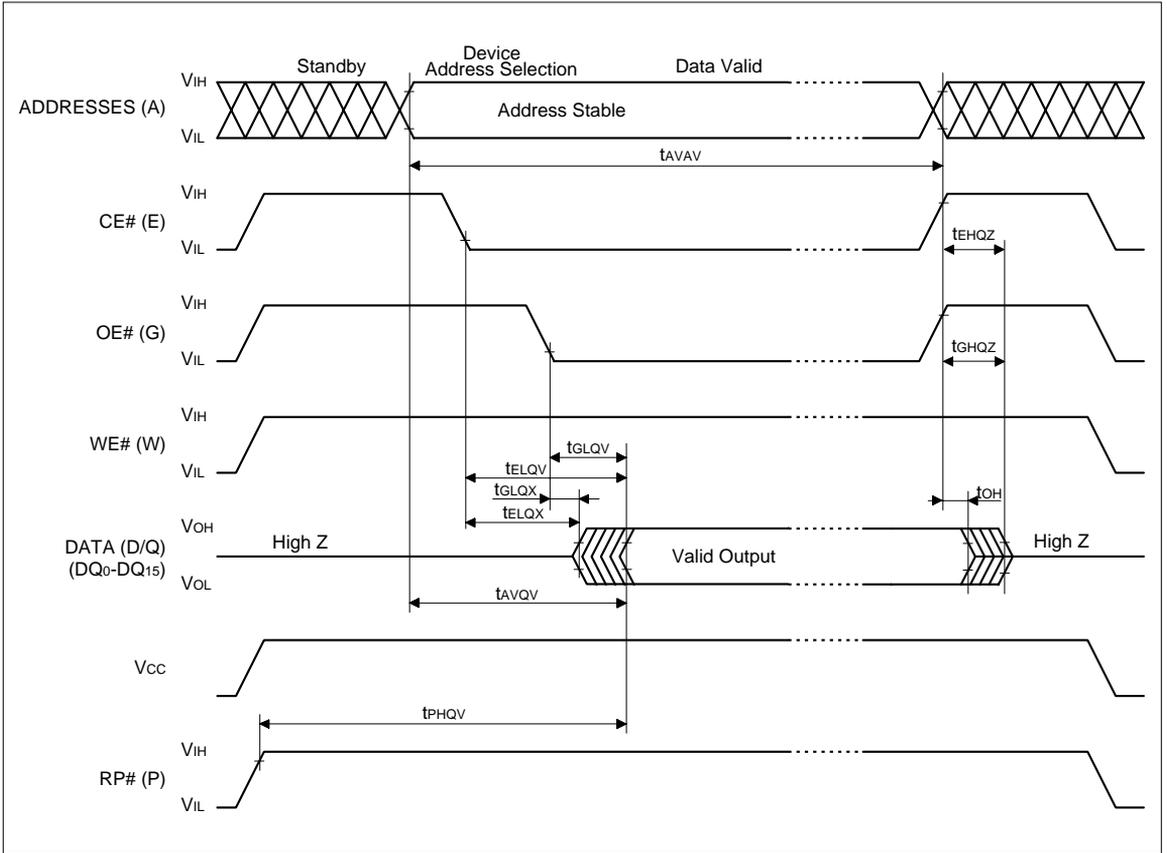


Fig. 11 AC Waveform for Read Operations

6.2.5 AC CHARACTERISTICS - WRITE OPERATIONS (NOTE 1)

• Vcc = 2.7 to 3.6 V, TA = 0 to +70°C or -40 to +85°C

VERSIONS			LH28F800BG-L85 LH28F800BGH-L85		LH28F800BG-L12 LH28F800BGH-L12		UNIT
SYMBOL	PARAMETER	NOTE	MIN.	MAX.	MIN.	MAX.	
tAVAV	Write Cycle Time		120		150		ns
tPHWL	RP# High Recovery to WE# Going Low	2	1		1		µs
tELWL	CE# Setup to WE# Going Low		10		10		ns
tWLWH	WE# Pulse Width		50		50		ns
tPHWH	RP# VIH Setup to WE# Going High	2	100		100		ns
tSHWH	WP# VIH Setup to WE# Going High	2	100		100		ns
tVPWH	VPP Setup to WE# Going High	2	100		100		ns
tAVWH	Address Setup to WE# Going High	3	50		50		ns
tDVWH	Data Setup to WE# Going High	3	50		50		ns
tWHDX	Data Hold from WE# High		5		5		ns
tWHAX	Address Hold from WE# High		5		5		ns
tWHEH	CE# Hold from WE# High		10		10		ns
tWHWL	WE# Pulse Width High		30		30		ns
tWHRL	WE# High to RY/BY# Going Low			100		100	ns
tWHGL	Write Recovery before Read		0		0		ns
tQVVL	VPP Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns
tQVPH	RP# VIH Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns
tQVSL	WP# VIH Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns

NOTES :

- Read timing characteristics during block erase and word write operations are the same as during read-only operations. Refer to **Section 6.2.4 "AC CHARACTERISTICS"** for read-only operations.
- Sampled, not 100% tested.
- Refer to **Table 3** for valid AIN and DIN for block erase or word write.
- VPP should be held at VPPH1/2/3 (and if necessary RP# should be held at VIH) until determination of block erase or word write success (SR.1/3/4/5 = 0 : on Boot Blocks, SR.3/4/5 = 0 : on Parameter Blocks and Main Blocks).

6.2.5 AC CHARACTERISTICS - WRITE OPERATIONS (contd.) (NOTE 1)

• Vcc = 3.3±0.3 V, TA = 0 to +70°C or -40 to +85°C

VERSIONS			LH28F800BG-L85 LH28F800BGH-L85		LH28F800BG-L12 LH28F800BGH-L12		UNIT
SYMBOL	PARAMETER	NOTE	MIN.	MAX.	MIN.	MAX.	
tAVAV	Write Cycle Time		100		130		ns
tPHWL	RP# High Recovery to WE# Going Low	2	1		1		µs
tELWL	CE# Setup to WE# Going Low		10		10		ns
tWLWH	WE# Pulse Width		50		50		ns
tPHHWH	RP# VIH Setup to WE# Going High	2	100		100		ns
tSHWH	WP# VIH Setup to WE# Going High	2	100		100		ns
tVPWH	VPP Setup to WE# Going High	2	100		100		ns
tAVWH	Address Setup to WE# Going High	3	50		50		ns
tDVWH	Data Setup to WE# Going High	3	50		50		ns
tWHDX	Data Hold from WE# High		5		5		ns
tWHAX	Address Hold from WE# High		5		5		ns
tWHEH	CE# Hold from WE# High		10		10		ns
tWHWL	WE# Pulse Width High		30		30		ns
tWHRL	WE# High to RY/BY# Going Low			100		100	ns
tWHGL	Write Recovery before Read		0		0		ns
tQVVL	VPP Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns
tQVPH	RP# VIH Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns
tQVSL	WP# VIH Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns

NOTES :

- Read timing characteristics during block erase and word write operations are the same as during read-only operations. Refer to **Section 6.2.4 "AC CHARACTERISTICS"** for read-only operations.
- Sampled, not 100% tested.
- Refer to **Table 3** for valid A_{IN} and D_{IN} for block erase or word write.
- VPP should be held at VPPH1/2/3 (and if necessary RP# should be held at VIH) until determination of block erase or word write success (SR.1/3/4/5 = 0 : on Boot Blocks, SR.3/4/5 = 0 : on Parameter Blocks and Main Blocks).

6.2.5 AC CHARACTERISTICS - WRITE OPERATIONS (contd.) (NOTE 1)

• $V_{CC} = 5.0 \pm 0.25 \text{ V}$, $5.0 \pm 0.5 \text{ V}$, $T_A = 0 \text{ to } +70^\circ\text{C}$ or $-40 \text{ to } +85^\circ\text{C}$

VERSIONS		V _{CC} ±0.25 V	(NOTE 5) LH28F800BG-L85 LH28F800BGH-L85		(NOTE 6) LH28F800BG-L85 LH28F800BGH-L85		(NOTE 6) LH28F800BG-L12 LH28F800BGH-L12		UNIT
			V _{CC} ±0.5 V		MIN.	MAX.	MIN.	MAX.	
SYMBOL	PARAMETER	NOTE	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
t _{AVAV}	Write Cycle Time		85		90		120		ns
t _{PHWL}	RP# High Recovery to WE# Going Low	2	1		1		1		µs
t _{ELWL}	CE# Setup to WE# Going Low		10		10		10		ns
t _{WLWH}	WE# Pulse Width		40		40		40		ns
t _{PHWH}	RP# V _{HH} Setup to WE# Going High	2	100		100		100		ns
t _{SHWH}	WP# V _{IH} Setup to WE# Going High	2	100		100		100		ns
t _{VPWH}	V _{PP} Setup to WE# Going High	2	100		100		100		ns
t _{AVWH}	Address Setup to WE# Going High	3	40		40		40		ns
t _{DVWH}	Data Setup to WE# Going High	3	40		40		40		ns
t _{WHDX}	Data Hold from WE# High		5		5		5		ns
t _{WHAX}	Address Hold from WE# High		5		5		5		ns
t _{WHEH}	CE# Hold from WE# High		10		10		10		ns
t _{WHWL}	WE# Pulse Width High		30		30		30		ns
t _{WHRL}	WE# High to RY/BY# Going Low			90		90		90	ns
t _{WHGL}	Write Recovery before Read		0		0		0		ns
t _{QVVL}	V _{PP} Hold from Valid SRD, RY/BY# High	2, 4	0		0		0		ns
t _{QVPH}	RP# V _{HH} Hold from Valid SRD, RY/BY# High	2, 4	0		0		0		ns
t _{QVSL}	WP# V _{IH} Hold from Valid SRD, RY/BY# High	2, 4	0		0		0		ns

NOTES :

1. Read timing characteristics during block erase and word write operations are the same as during read-only operations. Refer to **Section 6.2.4 "AC CHARACTERISTICS"** for read-only operations.
2. Sampled, not 100% tested.
3. Refer to **Table 3** for valid A_{IN} and D_{IN} for block erase or word write.
4. V_{PP} should be held at V_{PPH1/2/3} (and if necessary RP# should be held at V_{HH}) until determination of block erase or word write success (SR.1/3/4/5 = 0 : on Boot Blocks, SR.3/4/5 = 0 : on Parameter Blocks and Main Blocks).
5. See **Fig. 8 "Transient Input/Output Reference Waveform"** and **Fig. 10 "Transient Equivalent Testing Load Circuit"** (High Seed Configuration) for testing characteristics.
6. See **Fig. 9 "Transient Input/Output Reference Waveform"** and **Fig. 10 "Transient Equivalent Testing Load Circuit"** (Standard Configuration) for testing characteristics.

6.2.6 ALTERNATIVE CE#-CONTROLLED WRITES (NOTE 1)

• Vcc = 2.7 to 3.6 V, TA = 0 to +70°C or -40 to +85°C

VERSIONS			LH28F800BG-L85 LH28F800BGH-L85		LH28F800BG-L12 LH28F800BGH-L12		UNIT
SYMBOL	PARAMETER	NOTE	MIN.	MAX.	MIN.	MAX.	
tAVAV	Write Cycle Time		120		150		ns
tPHEL	RP# High Recovery to CE# Going Low	2	1		1		µs
tWLEL	WE# Setup to CE# Going Low		0		0		ns
tELEH	CE# Pulse Width		70		70		ns
tPHHEH	RP# V _{HH} Setup to CE# Going High	2	100		100		ns
tSHEH	WP# V _{IH} Setup to CE# Going High	2	100		100		ns
tVPEH	V _{PP} Setup to CE# Going High	2	100		100		ns
tAVEH	Address Setup to CE# Going High	3	50		50		ns
tDVEH	Data Setup to CE# Going High	3	50		50		ns
tEHDX	Data Hold from CE# High		5		5		ns
tEHAX	Address Hold from CE# High		5		5		ns
tEHWH	WE# Hold from CE# High		0		0		ns
tEHEL	CE# Pulse Width High		25		25		ns
tEHRL	CE# High to RY/BY# Going Low			100		100	ns
tEHGL	Write Recovery before Read		0		0		ns
tQVVL	V _{PP} Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns
tQVPH	RP# V _{HH} Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns
tQVSL	WP# V _{IH} Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns

NOTES :

- In systems where CE# defines the write pulse width (within a longer WE# timing waveform), all setup, hold, and inactive WE# times should be measured relative to the CE# waveform.
- Sampled, not 100% tested.
- Refer to **Table 3** for valid A_{IN} and D_{IN} for block erase or word write.
- V_{PP} should be held at V_{PPH1/2/3} (and if necessary RP# should be held at V_{HH}) until determination of block erase or word write success (SR.1/3/4/5 = 0 : on Boot Blocks, SR.3/4/5 = 0 : on Parameter Blocks and Main Blocks).

6.2.6 ALTERNATIVE CE#-CONTROLLED WRITES (contd.) (NOTE 1)

• Vcc = 3.3±0.3 V, TA = 0 to +70°C or -40 to +85°C

VERSIONS			LH28F800BG-L85 LH28F800BGH-L85		LH28F800BG-L12 LH28F800BGH-L12		UNIT
SYMBOL	PARAMETER	NOTE	MIN.	MAX.	MIN.	MAX.	
tAVAV	Write Cycle Time		100		130		ns
tPHEL	RP# High Recovery to CE# Going Low	2	1		1		µs
tWLEL	WE# Setup to CE# Going Low		0		0		ns
tELEH	CE# Pulse Width		70		70		ns
tPHHEH	RP# V _{HH} Setup to CE# Going High	2	100		100		ns
tSHEH	WP# V _{IH} Setup to CE# Going High	2	100		100		ns
tVPEH	V _{PP} Setup to CE# Going High	2	100		100		ns
tAVEH	Address Setup to CE# Going High	3	50		50		ns
tDVEH	Data Setup to CE# Going High	3	50		50		ns
tEHDx	Data Hold from CE# High		5		5		ns
tEHAX	Address Hold from CE# High		5		5		ns
tEHWH	WE# Hold from CE# High		0		0		ns
tEHEL	CE# Pulse Width High		25		25		ns
tEHRL	CE# High to RY/BY# Going Low			100		100	ns
tEHGL	Write Recovery before Read		0		0		ns
tQVVL	V _{PP} Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns
tQVPH	RP# V _{HH} Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns
tQVSL	WP# V _{IH} Hold from Valid SRD, RY/BY# High	2, 4	0		0		ns

NOTES :

- In systems where CE# defines the write pulse width (within a longer WE# timing waveform), all setup, hold, and inactive WE# times should be measured relative to the CE# waveform.
- Sampled, not 100% tested.
- Refer to **Table 3** for valid A_{IN} and D_{IN} for block erase or word write.
- V_{PP} should be held at V_{PPH1/2/3} (and if necessary RP# should be held at V_{HH}) until determination of block erase or word write success (SR.1/3/4/5 = 0 : on Boot Blocks, SR.3/4/5 = 0 : on Parameter Blocks and Main Blocks).

6.2.6 ALTERNATIVE CE#-CONTROLLED WRITES (contd.) (NOTE 1)

• Vcc = 5.0±0.25 V, 5.0±0.5 V, TA = 0 to +70°C or -40 to +85°C

VERSIONS		Vcc±0.25 V	(NOTE 5) LH28F800BG-L85 LH28F800BGH-L85				(NOTE 6) LH28F800BG-L12 LH28F800BGH-L12		UNIT
		Vcc±0.5 V			MIN.	MAX.	MIN.	MAX.	
SYMBOL	PARAMETER	NOTE	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
tAVAV	Write Cycle Time		85		90		120		ns
tPHEL	RP# High Recovery to CE# Going Low	2	1		1		1		µs
tWLEL	WE# Setup to CE# Going Low		0		0		0		ns
tELEH	CE# Pulse Width		50		50		50		ns
tPHHEH	RP# V _{HH} Setup to CE# Going High	2	100		100		100		ns
tSHEH	WP# V _{IH} Setup to CE# Going High	2	100		100		100		ns
tVPEH	V _{PP} Setup to CE# Going High	2	100		100		100		ns
tAVEH	Address Setup to CE# Going High	3	40		40		40		ns
tDVEH	Data Setup to CE# Going High	3	40		40		40		ns
tEHDX	Data Hold from CE# High		5		5		5		ns
tEHAX	Address Hold from CE# High		5		5		5		ns
tEHWH	WE# Hold from CE# High		0		0		0		ns
tEHEL	CE# Pulse Width High		25		25		25		ns
tEHRL	CE# High to RY/BY# Going Low			90		90		90	ns
tEHGL	Write Recovery before Read		0		0		0		ns
tQVVL	V _{PP} Hold from Valid SRD, RY/BY# High	2, 4	0		0		0		ns
tQVPH	RP# V _{HH} Hold from Valid SRD, RY/BY# High	2, 4	0		0		0		ns
tQVSL	WP# V _{IH} Hold from Valid SRD, RY/BY# High	2, 4	0		0		0		ns

NOTES :

- In systems where CE# defines the write pulse width (within a longer WE# timing waveform), all setup, hold, and inactive WE# times should be measured relative to the CE# waveform.
- Sampled, not 100% tested.
- Refer to **Table 3** for valid A_{IN} and D_{IN} for block erase or word write.
- V_{PP} should be held at V_{PPH1/2/3} (and if necessary RP# should be held at V_{HH}) until determination of block erase or word write success (SR.1/3/4/5 = 0 : on Boot Blocks, SR.3/4/5 = 0 : on Parameter Blocks and Main Blocks).
- See **Fig. 8 "Transient Input/Output Reference Waveform"** and **Fig. 10 "Transient Equivalent Testing Load Circuit"** (High Speed Configuration) for testing characteristics.
- See **Fig. 9 "Transient Input/Output Reference Waveform"** and **Fig. 10 "Transient Equivalent Testing Load Circuit"** (Standard Configuration) for testing characteristics.

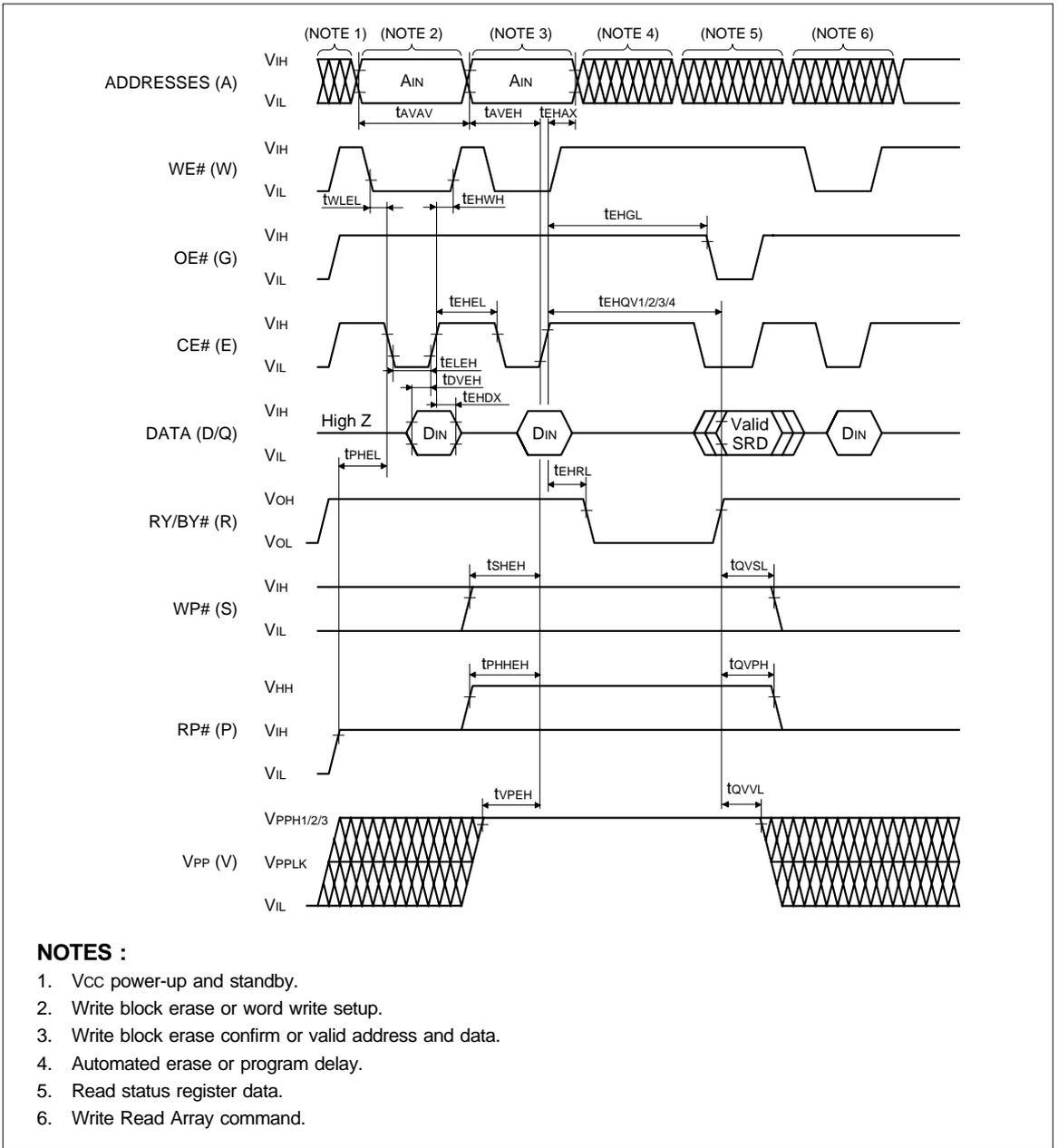


Fig. 13 AC Waveform for CE#-Controlled Write Operations

6.2.7 RESET OPERATIONS

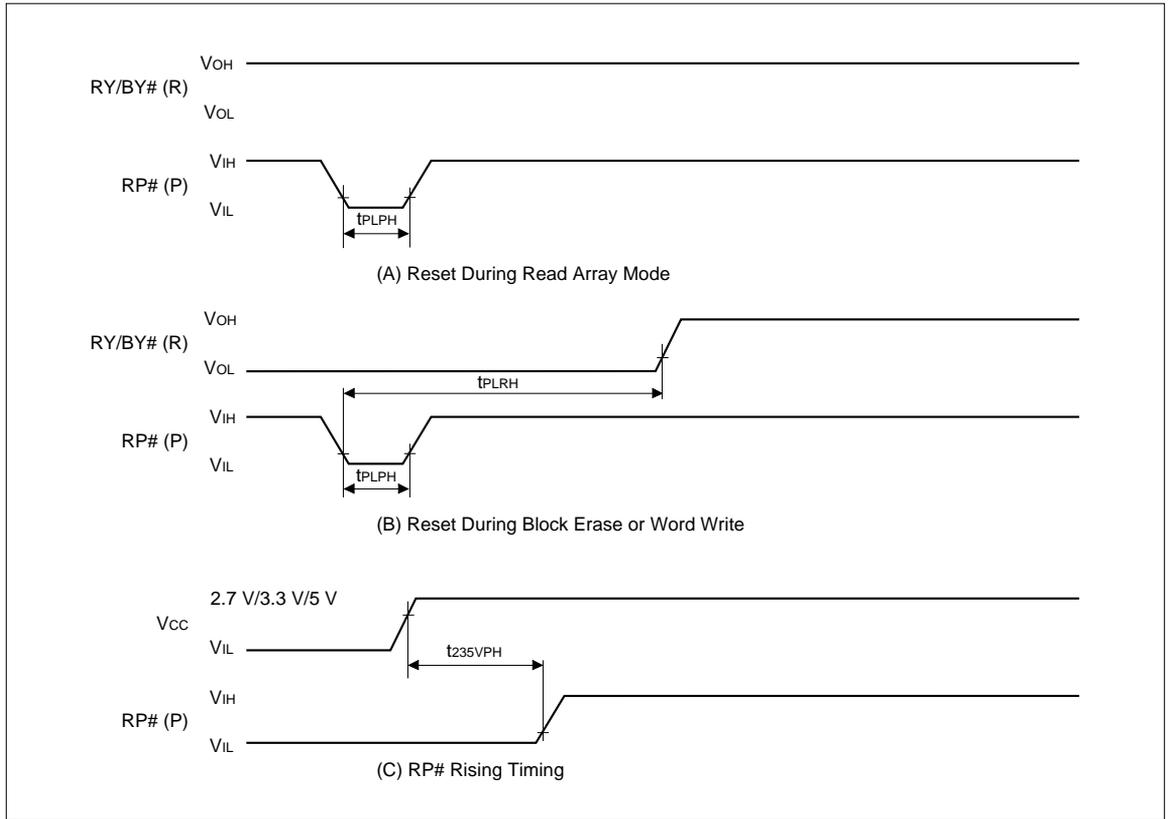


Fig. 14 AC Waveform for Reset Operation

Reset AC Specifications (NOTE 1)

SYMBOL	PARAMETER	NOTE	V _{CC} = 2.7 to 3.6 V		V _{CC} = 3.3±0.3 V		V _{CC} = 5.0±0.5 V		UNIT
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
t _{PLPH}	RP# Pulse Low Time (If RP# is tied to V _{CC} , this specification is not applicable)		100		100		100		ns
t _{PLRH}	RP# Low to Reset during Block Erase or Word Write	2, 3		22		20		12	µs
t _{235VPH}	V _{CC} 2.7 V to RP# High V _{CC} 3.0 V to RP# High V _{CC} 4.5 V to RP# High	4	100		100		100		ns

NOTES :

1. These specifications are valid for all product versions (packages and speeds).
2. If RP# is asserted while a block erase or word write operation is not executing, the reset will complete within 100 ns.
3. A reset time, t_{PHQV}, is required from the latter of RY/BY# or RP# going high until outputs are valid.
4. When the device power-up, holding RP#-low minimum 100 ns is required after V_{CC} has been in predefined range and also has been in stable there.

6.2.8 BLOCK ERASE AND WORD WRITE PERFORMANCE (NOTE 3, 4)

• $V_{CC} = 2.7$ to 3.6 V, $T_A = 0$ to $+70^\circ\text{C}$ or -40 to $+85^\circ\text{C}$

SYMBOL	PARAMETER		NOTE	$V_{PP} = 2.7$ to 3.6 V			$V_{PP} = 5.0 \pm 0.5$ V			$V_{PP} = 12.0 \pm 0.6$ V			UNIT
				MIN.	TYP.(NOTE 1)	MAX.	MIN.	TYP.(NOTE 1)	MAX.	MIN.	TYP.(NOTE 1)	MAX.	
tWHQV1	Word Write Time	32 k-Word Block	2		44.6			17.7			12.6		μs
tEHQV1		4 k-Word Block	2		45.9			26.1			24.5		μs
	Block Write Time	32 k-Word Block	2		1.46			0.58			0.42		s
		4 k-Word Block	2		0.19			0.11			0.11		s
tWHQV2	Block Erase Time	32 k-Word Block	2		1.14			0.61			0.51		s
tEHQV2		4 k-Word Block	2		0.38			0.32			0.31		s
tWHRH1	Word Write Suspend Latency Time to Read				7	8		6	8		6	7	μs
tWHRH2	Erase Suspend Latency Time to Read				18	22		11	14		11	14	μs

• $V_{CC} = 3.3 \pm 0.3$ V, $T_A = 0$ to $+70^\circ\text{C}$ or -40 to $+85^\circ\text{C}$

SYMBOL	PARAMETER		NOTE	$V_{PP} = 3.3 \pm 0.3$ V			$V_{PP} = 5.0 \pm 0.5$ V			$V_{PP} = 12.0 \pm 0.6$ V			UNIT
				MIN.	TYP.(NOTE 1)	MAX.	MIN.	TYP.(NOTE 1)	MAX.	MIN.	TYP.(NOTE 1)	MAX.	
tWHQV1	Word Write Time	32 k-Word Block	2		44			17.3			12.3		μs
tEHQV1		4 k-Word Block	2		45			25.6			24		μs
	Block Write Time	32 k-Word Block	2		1.44			0.57			0.41		s
		4 k-Word Block	2		0.19			0.11			0.1		s
tWHQV2	Block Erase Time	32 k-Word Block	2		1.11			0.59			0.5		s
tEHQV2		4 k-Word Block	2		0.37			0.31			0.3		s
tWHRH1	Word Write Suspend Latency Time to Read				6	7		5	7		5	6	μs
tWHRH2	Erase Suspend Latency Time to Read				16.2	20		9.6	12		9.6	12	μs

NOTES :

1. Typical values measured at $T_A = +25^\circ\text{C}$ and nominal voltages. Subject to change based on device characterization.
2. Excludes system-level overhead.
3. These performance numbers are valid for all speed versions.
4. Sampled, not 100% tested.

6.2.8 BLOCK ERASE AND WORD WRITE PERFORMANCE (contd.) (NOTE 3, 4)

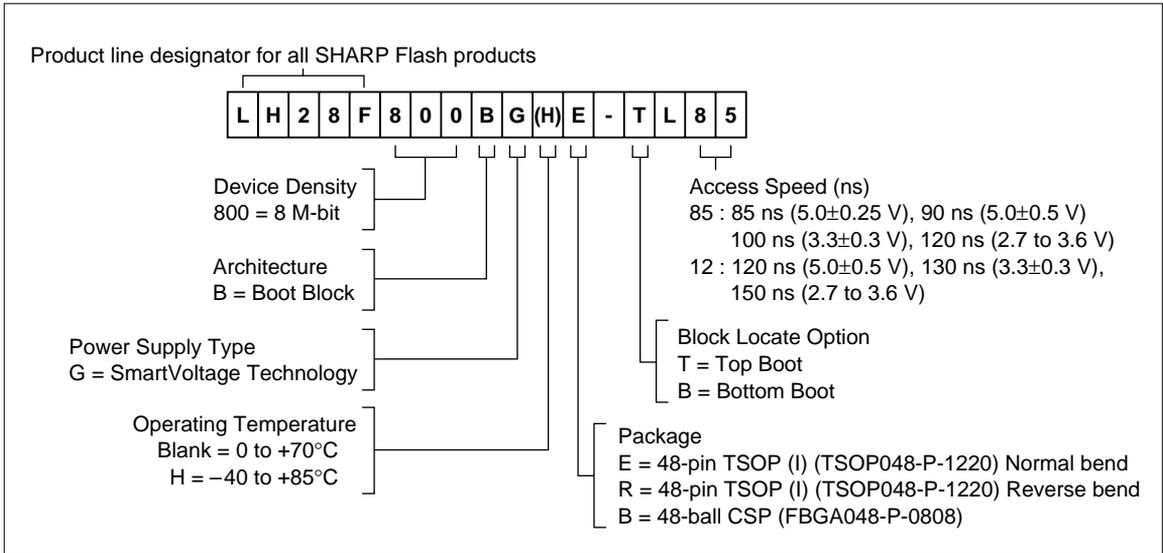
• $V_{CC} = 5.0 V \pm 0.25 V$, $5.0 \pm 0.5 V$, $T_A = 0$ to $+70^\circ C$ or -40 to $+85^\circ C$

SYMBOL	PARAMETER		NOTE	$V_{PP} = 5.0 \pm 0.5 V$			$V_{PP} = 12.0 \pm 0.6 V$			UNIT
				MIN.	TYP.(NOTE 1)	MAX.	MIN.	TYP.(NOTE 1)	MAX.	
t _{WHQV1} t _{EHQV1}	Word Write Time	32 k-Word Block	2		12.2			8.4		μs
		4 k-Word Block	2		18.3			17		μs
	Block Write Time	32 k-Word Block	2		0.4			0.28		s
		4 k-Word Block	2		0.08			0.07		s
t _{WHQV2} t _{EHQV2}	Block Erase Time	32 k-Word Block	2		0.46			0.39		s
		4 k-Word Block	2		0.26			0.25		s
t _{WHRH1} t _{EHRH1}	Word Write Suspend Latency Time to Read				5	6		4	5	μs
t _{WHRH2} t _{EHRH2}	Erase Suspend Latency Time to Read				9.6	12		9.6	12	μs

NOTES :

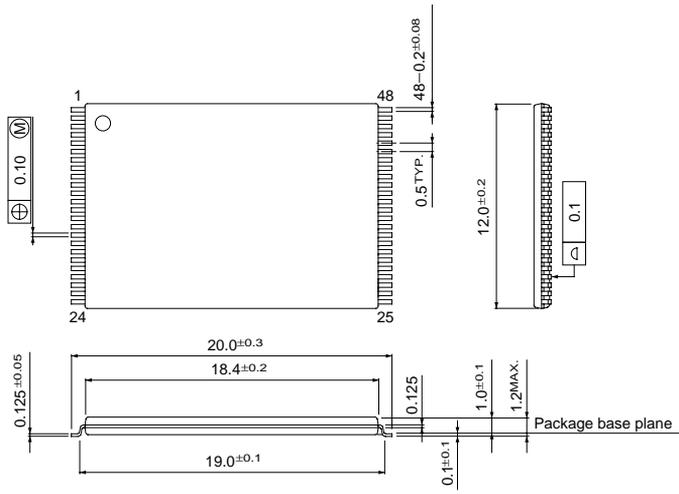
1. Typical values measured at $T_A = +25^\circ C$ and nominal voltages. Subject to change based on device characterization.
2. Excludes system-level overhead.
3. These performance numbers are valid for all speed versions.
4. Sampled, not 100% tested.

7 ORDERING INFORMATION

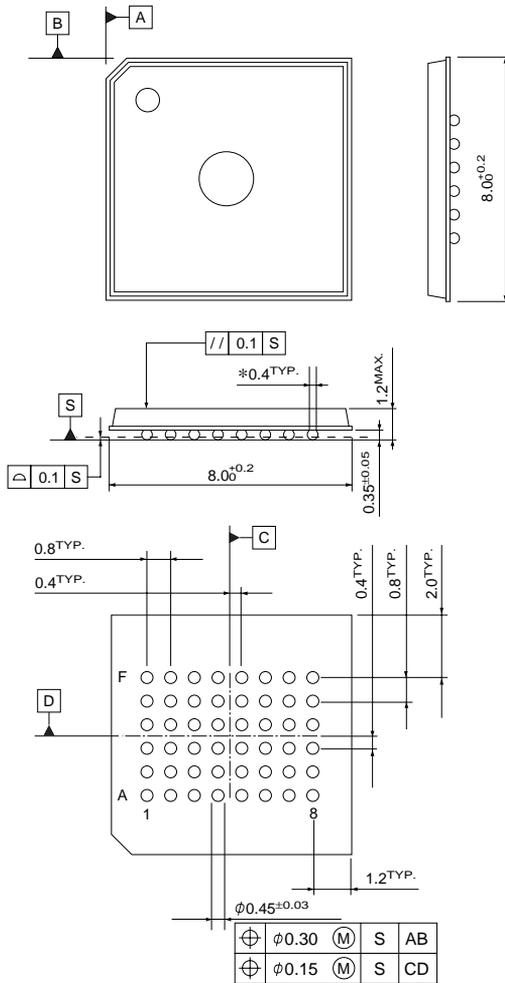


OPTION	ORDER CODE	VALID OPERATIONAL COMBINATIONS			
		V _{CC} = 2.7 to 3.6 V 50 pF load, 1.35 V I/O Levels	V _{CC} = 3.3±0.3 V 50 pF load, 1.5 V I/O Levels	V _{CC} = 5.0±0.5 V 100 pF load, TTL I/O Levels	V _{CC} = 5.0±0.25 V 30 pF load, 1.5 V I/O Levels
1	LH28F800BGXX-XL85	120 ns	100 ns	90 ns	85 ns
2	LH28F800BGXX-XL12	150 ns	130 ns	120 ns	

48 TSOP (TSOP048-P-1220)



48 CSP (FBGA048-P-0808)



*Land hole diameter for ball mounting